ADS7869

Analog Motor Control Front-End with Simultaneous Sampling on Seven S/H Capacitors and Three 1MSPS, 12-Bit, 12-Channel ADCs

Data Manual

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Contents

Fe	atures .			. 1
Аp	plicatio	ns		. 1
De	scriptio	n		. 1
	1.1	Ordering	g Information	. 2
	1.2	Absolute	e Maximum Ratings	. 2
	1.3	Recomn	nended Operating Conditions	. 2
	1.4	Package	e Dissipation Ratings	. 2
	1.5	Electrica	al Characteristics	. 3
	1.6	Pinout D	Drawing	. 6
	1.7	Pin Fund	ctions	. 7
	1.8	Basic Ci	ircuit Configuration	. 9
	1.9	Typical /	Application Circuit	10
	1.10	Typical (Characteristics	11
	1.11	Function	nal Block Diagram	15
2	Analog	g Section	- 	16
	2.1	Fully Dif	ferential Analog Inputs	16
		2.1.1	Analog-to-Digital Converter Inputs	16
		2.1.2	Window Comparator Inputs	17
		2.1.3	Sign Comparator Inputs	17
	2.2	Analog-	To-Digital Converter	17
		2.2.1	HOLD1, HOLD2	17
		2.2.2	Clock	18
		2.2.3	Reset	18
		2.2.4	Gain Adjustment	18
		2.2.5	Offset Adjustment	18
		2.2.6	Transition Noise	19
	2.3	Sign Co	mparators	19
	2.4	Window	Comparators	21
	2.5	8-Bit Dig	gital-to-Analog Converter	22
	2.6	Internal	Reference	22
	2.7	Groundi	ng	22
	2.8	Supply		22



SBAS253C - MAY 2003 - REVISED JANUARY 2005

3	Digital	Section .		23
	3.1	Introduction	on	23
	3.2	VECANA	Interface	24
		3.2.1	Input Channel Selection	25
		3.2.2	VECANA Timing Characteristics	26
		3.2.3	WINCLK Selection	27
	3.3	Serial Per	ripheral Interface (SPI)	27
		3.3.1	SPI Timing Characteristics	29
	3.4	Parallel In	nterface	30
		3.4.1	Parallel Read and Write Control	30
		3.4.2	Mode 10 Bus Access	31
		3.4.3	Mode 11 Bus Access (Standard Mode)	33
		3.4.4	Mode 11 Bus Access (TMS320c54xx DSP Family-Compatible Mode)	35
	3.5	Register N	Мар	37
	3.6	Register [Descriptions	39
		3.6.1	FIFO Data Register (00 _H)	39
		3.6.2	Offset Registers (01 _H to 0C _H)	40
		3.6.3	Gain Registers (0D _H to 18 _H)	40
		3.6.4	WINDAC Register (19 _H)	40
		3.6.5	Control Register (1A _H)	41
		3.6.6	Counter Control/Status Register (1BH)	42
		3.6.7	Edge Count Register (1C _H , 1D _H , 20 _H and 21 _H)	43
		3.6.8	Edge Period Register (1E _H and 22 _H)	43
		3.6.9	Edge Time Period Register (1F _H and 23 _H)	44
		3.6.10	FIFO Test Register (24 _H)	44
		3.6.11	Comparator Test Register (25 _H)	45
		3.6.12	Interrupt Register (26 _H)	46
		3.6.13	Parallel Register (27 _H)	47
		3.6.14	Reset Register (28 _H)	48
	3.7	FIFO		49
		3.7.1	DAV Timing Characteristics	51
	3.8	Digital Co	unter Modules	52
		3.8.1	Operation	52
		3.8.2	Digital Noise Filter	53
		3.8.3	Binary Counters and Registers	56
	3.9	Interrupt .		58
	3.10			
		3.10.1	Reset Timing Characteristics	58



SBAS253C - MAY 2003 - REVISED JANUARY 2005

List of Illustrations

–1. Typical Motor Control Application	10
–2. Functional Diagram	15
-3. Equivalent Input Circuit to the ADCs	16
-4. Equivalent Input Circuit of the Window Comparators	17
–5. Histogram of 8000 Conversions	19
–6. Typical Transfer Function of a Sign Comparator	19
-7. Position Sensor Comparator Overdrive	20
–8. Current Sign Comparator Overdrive	20
–9. Typical Transfer Function of a Window Comparator	21
-10. VECANA Access	26
–11. One SPI Transfer Cycle	27
–12. Continuous SPI Transfer Cycle	28
-13. SPI Access	29
-14. Mode 10 Read Access	31
-15. Mode 10 Write Access	32
-16. Mode 11 Read Access (Standard Mode)	33
-17. Mode 11 Write Access (Standard Mode)	34
-18. Mode 11 Read Access (TMS320c54xx mode)	35
-19. Mode 11 Write Access (TMS320c54xx mode)	36
–20. FIFO Structure	49
–21. FIFO Block Diagram	50
–22. Timing of the DAV Signal	51
–23. Block Diagram of a Counter Module	52
–24. Digital Noise Filter Block Diagram	53
–25. Timing Diagram of the Counter Signals with the Digital Noise Filter Enabled	54
–26. Timing Diagram of the Counter Signals with the Digital Noise Filter Disabled	55
–27. Detail Counter Block Diagram	56
–28. Detail Counter Timing Diagram	57
_29 Timing Diagram of the Reset Signal RST	58



SBAS253C - MAY 2003 - REVISED JANUARY 2005

List of Tables

1–1. Select	tion of Interface Mode	23
1-2. Mode	vs Pin Functions	23
1-3. DAC I	Input/Output Relationships	24
1-4. VECA	ANA Gain Select Information	24
1-5. 13-bit	: VECANA ADIN Word Format	25
1-6. Contro	ols for Input Multiplexers and Sample Holds	25
1-7. Windo	ow Comparator Clock	27
1-8. SPI W	Vrite 24-bit Word Format	27
1-9. Host F	Parallel Port Operation	30
1-10. Regi	ister Map Write 16-bit Data	37
1-11. Regi:	ister Map Read 16-bit Data	38
1–12. FIFC	Output Word Format 3	39
1–13. Offse	et Registers	10
1-14. Gain	n Registers	4 C
1–15. WINI	DAC Register	4 C
1-16. Cont	trol Registers	11
1-17. Cour	nter/Control Status Register	12
1-18. Sync	chronous Latched Edge Count Register 4	13
1-19. Asyn	nchronous Latched Edge Count Register	13
1–20. Edge	e Period Register	13
1–21. Edge	e Time Period Register	14
1-22. FIFC	D Test Register	14
1-23. Com	nparator Test Register	15
1-24. Inter	rupt Register	16
1-25. Para	allel Register	17
1–26. Rese	et Register	48
1_27 FIFC	2.16-bit Data Read Format	10







STRUMENTS

FEATURES

- Seven Simultaneously-Sampling Sample-and-Hold (S/H) Capacitors
- Fully Differential Inputs
- Flexible Digital Interface with Four Modes
 - One Mode 100% Software-Compatible to VECANA01
 - SPI and Two Parallel Modes
- Two Up-Down Counter Modules On-Chip
- 12-Bit System Gain Adjustment for Every Channel
- 12-Bit Accurate System Offset Adjustment for Every Channel

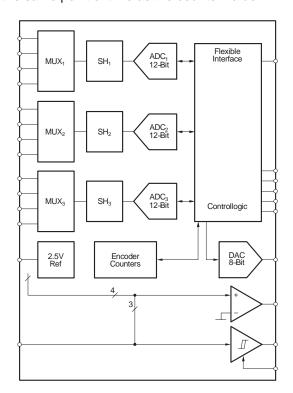
APPLICATIONS

Motor Control

DESCRIPTION

The ADS7869 is a motor control front-end that includes three analog-to-digital converters (ADCs) with a total of seven sample-and-hold capacitors and 12 fully differential input channels. There are four sign comparators connected to four input channels. There are also three additional fully differential inputs; each input is connected to a window comparator and a sign comparator.

In addition, the ADS7869 also offers a very flexible digital interface with a parallel port that can be configured to different standards. Furthermore, a serial peripheral interface (SPI) and a specialized serial interface with three data lines (VECANA01 mode) are provided. This allows the ADS7869 to interface with most digital signal processors (DSPs) or microcontrollers. The chip is specialized for motor-control applications. For the position sensor analysis, two up–down counters are added on the silicon. This feature ensures that the analog input of the encoder is held at the same point of time as the counter value.







SBAS253C - MAY 2003 - REVISED JANUARY 2005

1.1 ORDERING INFORMATION(1)

PRODUCT	MAXIMUM INTEGRAL LINEARITY ERROR (LSB)	NO MISSING CODES ERROR (LSB)	PACKAGE- LEAD	PACKAGE DESIGNATOR	SPECIFIED TEMPERATURE RANGE	ORDERING NUMBER	TRANSPORT MEDIA, QUANTITY
4 D O 7 0 0 0 1	.0	44	TOED 400	D.7T	4000 1 0500	ADS7869IPZTT	Tape and Reel, 250
ADS7869I	±2	11	TQFP-100	PZT	-40°C to +85°C	ADS7869IPZTR	Tape and Reel, 1000

⁽¹⁾ For the most current package and ordering information, see the Package Option Addendum located at the end of this data manual.

1.2 ABSOLUTE MAXIMUM RATINGS

over operating free-air temperature range unless otherwise noted(1)

	ADS7869I	UNIT
Supply voltage, AV _{DD} to AGND	-0.3 to 6	V
Supply voltage, BV _{DD} to BGND	-0.3 to 6	V
Analog input voltage with respect to AGND	AGND – 0.3 to AV _{DD} + 0.3	V
Reference input voltage with respect to AGND	AGND – 0.3 to AV _{DD} + 0.3	V
Digital input voltage with respect to BGND	BGND – 0.3 to BV _{DD} + 0.3	V
Ground voltage difference AGND to BGND	± 0.3	V
Input current to any pin except supply	-10 to +10	mA
Operating virtual junction temperature range, T _J	-40 to +150	°C
Operating free-air temperature range, T _A	-40 to +85	°C
Storage temperature range, T _{STG}	-65 to +150	°C
Lead temperature 1,6mm (1/16-inch) from case for 10 seconds	+260	°C

⁽¹⁾ Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under *Recommended Operating Conditions* is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

1.3 RECOMMENDED OPERATING CONDITIONS

		MIN	NOM	MAX	UNIT	
Supply Voltage, AGND to AVDD		4.5	5	5.5	V	
Supply Voltage, BGND to BVDD	Low-Voltage Levels	2.7		3.6	V	
	5V Logic Levels	4.5	5	5.5	V	
Reference Input Voltage		2.475	2.5	2.525	V	
Analog Inputs (also see Fully Differential Analog Inputs section)	+IN - (-IN)	-REF_ADC		+REF_ADC	٧	
Operating junction temperature range, TJ	-	-40		+85		

1.4 PACKAGE DISSIPATION RATINGS

BOARD	PACKAGE	$R_{\Theta}JC$	$R_{\Theta}JA$	DERATING FACTOR ABOVE T _A = 25°C	$T_A \le 25^{\circ}C$ POWER RATING	T _A = 70°C POWER RATING	T _A = 85°C POWER RATING
Low-K(1)	PZT	3.5°C/W	45°C/W	22.222mW/°C	2778mW	1778mW	1444mW
High-K(2)	PZT	3.5°C/W	2.82°C/W	35.461mW/°C	4433mW	2837mW	2305mW

⁽¹⁾ The JEDEC Low-K (1s) board design used to derive this data was a 3-inch x 3-inch, two-layer board with 2-ounce copper traces on top of the board.

⁽²⁾ The JEDEC High-K (2s2p) board design used to derive this data was a 3-inch x 3-inch, multilayer board with 1-ounce internal power and ground planes and 2-ounce copper traces on the top and bottom of the board.

SBAS253C - MAY 2003 - REVISED JANUARY 2005

1.5 ELECTRICAL CHARACTERISTICS

Over recommended operating free-air temperature range at -40°C to $+85^{\circ}\text{C}$, $\text{AV}_{DD} = 5\text{V}$, $\text{BV}_{DD} = 3.3\text{V}$, $\text{V}_{REF} = \text{internal} +2.5\text{V}$, $\text{f}_{CLK} = 16\text{MHz}$, $\text{f}_{SAMPLE} = 1$ MSPS, unless otherwise noted.

PARAMETER	CONDITION	MIN	TYP(1)	MAX	UNIT	
Resolution		12			Bit	
Analog Input				•		
Full-scale Voltage, Differential	See Gain Adjustment	-REF_ADC		+REF_ADC	V	
Input Capacitance	,		10		pF	
Input Leakage Current			±1		nA	
CMRR	At DC		64	1	dB	
DC Accuracy						
No Missing Codes		11			Bit	
INL Integral Linearity Error			±1	±2.5	LSB	
DNL Differential Linearity Error			±0.65	±2	LSB	
V _{OS} Bipolar Offset Error	Synchronous Channels		2	±6	LSB	
V _{OS} Bipolar Offset Error	AX and BX Channels		5	±8	LSB	
VOS Bipolar Offset Match	IU, IV, and IW Channels		2.5	6	LSB	
V _{OS} Bipolar Offset Match	A1, B1, A2, and B2 Channels		0.5	3	LSB	
V _{OS} Bipolar Offset Match	AX and BX Channels		0.5	3	LSB	
TCV _{OS} Bipolar Offset Error Drift			1		μV/°C	
Gain Error	Max Input Range, Related to REFIN		0.05	1	%	
Gain Error	Every Other Input Range		1.5	4	%	
Gain Error Drift	Max Input Range, Related to REFIN		3		ppm/°C	
PSRR Power-Supply Rejection Ratio	4.5V < AV _{DD} < 5.5V		70		dB	
Sampling Dynamics						
t _{CONV} Conversion Time per ADC	$16MHz \le f_{CLK} \le 1MHz$	0.75		12	μS	
t _{AQ} Acquisition Time		250			ns	
Throughput Rate				1000	kSPS	
Aperture Delay				20	ns	
Aperture Delay Matching			1		ns	
Aperture Jitter			50		ps	
Clock Frequency		1		16	MHz	
AC Accuracy						
Total Harmonic Distortion THD	$V_{IN} = \pm 2.5 V_{PP}$ at 10kHz		-78		dB	
Signal-to-Noise Distortion SNR	$V_{IN} = \pm 2.5 V_{PP}$ at 10kHz		71		dB	
Signal-to-Noise + Distortion SINAD	$V_{IN} = \pm 2.5 V_{PP}$ at 10kHz		70		dB	
Digital Inputs ⁽²⁾						
Logic Family			CMOS			
VIH High-Level Input Voltage		0.7•V _{DD}		BV _{DD} + 0.3	V	
V _{IL} Low-Level Input Voltage		-0.3		0.3•V _{DD}	V	
I _{IN} Input Current	BV _{DD} to BGND			±50	nA	
C _I Input Capacitance			5		pF	
Digital Outputs ⁽²⁾						
Logic Family			CMOS			
V _{OH} High-Level Output Voltage	$BV_{DD} = 4.5V, I_{OH} = -100\mu A$	4.44			V	
V _{OL} Low-Level Output Voltage	$BV_{DD} = 4.5V, I_{OL} = +100\mu A$			0.5	V	
IOZ High-Impedance-State Output Current	$V_I = BV_{DD}$ to BGND			±50	nA	
Co Output Capacitance			5		pF _	
C _L Load Capacitance				30	pF	

⁽¹⁾ All values are at $T_A = +25^{\circ}C$.

⁽²⁾ Applies for 5.0V nominal supply: 4.5V < BV_{DD} < 5.5V.

⁽³⁾ Applies for 3.0V nominal supply: 2.7V < BV_{DD} < 3.6V.



SBAS253C - MAY 2003 - REVISED JANUARY 2005

1.5 ELECTRICAL CHARACTERISTICS (continued)

Over recommended operating free-air temperature range at -40 °C to +85 °C, $AV_{DD} = 5V$, $BV_{DD} = 3.3V$, $V_{REF} = internal +2.5V$, $f_{CLK} = 16MHz$, $f_{SAMPLE} = 1$ MSPS, unless otherwise noted.

			ADS7869I		
PARAMETER	CONDITION	MIN	TYP(1)	MAX	UNIT
Digital Inputs(3)				1	
Logic Family			LVCMOS		
VIH High-Level Input Voltage	BV _{DD} = 3.6V	2		BV _{DD} + 0.3	V
V _{II} Low-Level Input Voltage	BV _{DD} = 2.7V	-0.3		0.8	V
I _{IN} Input Current	$V_I = BV_{DD}$ to BGND			±50	nA
C _I Input Capacitance	. 55		5		pF
Digital Outputs(3)					·
Logic Family			LVCMOS		
VOH High-Level Output Voltage	$BV_{DD} = 2.7V, I_{OH} = -100\mu A$	BV _{DD} – 0.2			V
V _{OL} Low-Level Output Voltage	BV _{DD} = 2.7V, I _{OL} = +100μA			0.2	V
IOZ High-Impedance-State Output Current	$V_I = BV_{DD}$ to BGND			±50	nA
CO Output Capacitance			5		pF
C _L Load Capacitance				30	pF
Power Supply					•
AV _{DD} Analog Supply Voltage		4.5		5.5	V
BV _{DD} Buffer I/O Supply Voltage		2.7		5.5	V
AIDD Analog Supply Current			45	50	mA
BI _{DD} Buffer I/O Supply Voltage			2		mA
Power Dissipation				250	mW
Reference Output					
V _{REF} Reference Output Voltage	-40°C > t > +85°C	2.475	2.500	2.525	V
V _{REF} Reference Output Voltage	at 25°C	2.480	2.500	2.520	V
dV _{REF} /dT Reference Voltage Drift			±20		ppm/°C
PSRR Power-Supply Rejection Ratio			60		dB
IOUT Output Current	DC Current			1	μΑ
I _{SC} Short-Circuit Current			1		mA
t _{ON} Turn-On Setting Time			100		μs
Reference Input		•		•	
V _{IN} Reference Input Voltage		2.475	2.5	2.525	V
Input Resistance			100		ΜΩ
Input Capacitance			5		pF
Digital-to-Analog Converter					•
Resolution		8			Bits
Output Range	I _{OUT} = 0	0		2.49	V
INL Integral Linearity Error	551			±1	LSB
DNL Differential Linearity Error				±2	LSB
Offset Error			0.5	1	LSB
Full-Scale Error	FS = Internal Reference Voltage - 1LSB			±1	%
IOUT Output Current				0.5	μΑ
Output Settling Time	to 0.5LSB, no load capacitance		0.2	1	μs
Position Sensor Sign Comparator		•			
Input Range	Lower Voltage of Differential Inputs	0		AV _{DD} – 1.8	V
Offset Range		1	±5	±30	mV
Hysteresis		1	75	100	mV
Delay Time		1	25	150	ns

⁽¹⁾ All values are at $T_A = +25^{\circ}C$.

⁽²⁾ Applies for 5.0V nominal supply: 4.5V < BV_{DD} < 5.5V.

⁽³⁾ Applies for 3.0V nominal supply: 2.7V < BV_{DD} < 3.6V.



SBAS253C - MAY 2003 - REVISED JANUARY 2005

1.5 ELECTRICAL CHARACTERISTICS (continued)

Over recommended operating free-air temperature range at -40° C to $+85^{\circ}$ C, $AV_{DD} = 5$ V, $BV_{DD} = 3.3$ V, $V_{REF} = internal +2.5$ V, $f_{CLK} = 16$ MHz, $f_{SAMPLE} = 1$ MSPS, unless otherwise noted.

		ADS7869I			
PARAMETER	CONDITION	MIN	TYP(1)	MAX	UNIT
Current Sign Comparator	•	•	•		
Input Range	Lower Voltage of Differential Inputs	0		AV _{DD} – 1.8	V
Offset Range			±2	±20	mV
Hysteresis			10	30	mV
Delay Time			25	150	ns
Window Comparator					
Input Range		-0.3		$AV_{DD} + 0.3$	V
Offset Range			±10	±30	mV
Hysteresis		60	70	80	mV
Delay Time	f _{CLK} = 16MHz		250	375	ns
Threshold Voltage Input Range	(DAIN pin)	0.5	1	2.5	V

⁽¹⁾ All values are at $T_A = +25$ °C.

⁽²⁾ Applies for 5.0V nominal supply: 4.5V < BV_{DD} < 5.5V.

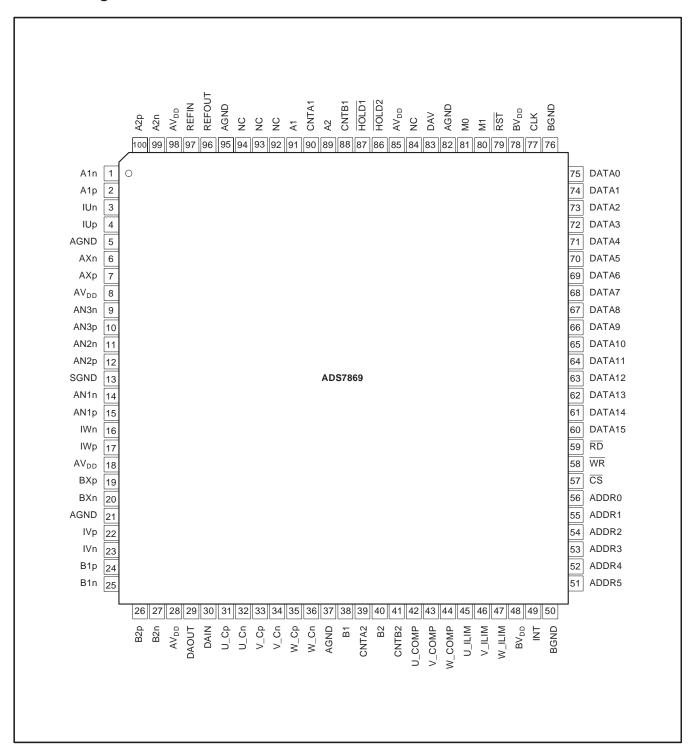
⁽³⁾ Applies for 3.0V nominal supply: 2.7V < BV_{DD} < 3.6V.

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1.6 PINOUT DRAWING

TQFP Package



SBAS253C - MAY 2003 - REVISED JANUARY 2005



1.7 **PIN FUNCTIONS**

TQFP Package

SIGNAL	PIN NUMBER	TYPE	DESCRIPTION					
ANALOG SIG	NALS							
		Analog	Input Signals of Position Sensors					
A1p	2	Analog In	Position Sensor 1, Analog Input of SIN, Positive Input					
A1n	1	Analog In	Position Sensor 1, Analog Input of SIN, Negative Input					
В1р	24	Analog In	Position Sensor 1, Analog Input of COS, Positive Input					
B1n	25	Analog In	Position Sensor 1, Analog Input of COS, Negative Input					
AXp	7	Analog In	Position Sensor X, Asynchronous Analog Input of SIN, Positive Input					
AXn	6	Analog In	Position Sensor X, Asynchronous Analog Input of SIN, Negative Input					
A2p	100	Analog In	Position Sensor 2, Analog Input of SIN, Positive Input					
A2n	99	Analog In	Position Sensor 2, Analog Input of SIN, Negative Input					
B2p	26	Analog In	Position Sensor 2, Analog Input of COS, Positive Input					
B2n	27	Analog In	Position Sensor 2, Analog Input of COS, Negative Input					
ВХр	19	Analog In	Position Sensor X, Asynchronous Analog Input of COS, Positive Input					
BXn	20	Analog In	Position Sensor X, Asynchronous Analog Input of COS, Negative Input					
		Coun	ter Signals of Position Sensors					
A1	91	Digital Out	Sign of SIN Signal, Position Sensor 1					
B1	38	Digital Out	Sign of COS Signal, Position Sensor 1					
A2	89	Digital Out	Sign of SIN Signal, Position Sensor 2					
B2	40	Digital Out	Sign of COS Signal, Position Sensor 2					
CNTA1	90	Digital In	Input Signal SIN to 16-bit Up/Down Counter 1					
CNTB1	88	Digital In	Input Signal COS to 16-bit Up/Down Counter 1					
CNTA2	39	Digital In	Input Signal SIN to 16-bit Up/Down Counter 2					
CNTB2	41	Digital In	Input Signal COS to 16-bit Up/Down Counter 2					
		Analog	Input Signals of Phase Currents					
IUp	4	Analog In	Phase U Current, Positive Input					
IUn	3	Analog In	Phase U Current, Negative Input					
IVp	22	Analog In	Phase V Current, Positive Input					
IVn	23	Analog In	Phase V Current, Negative Input					
IWp	17	Analog In	Phase W Current, Positive Input					
IWn	16	Analog In	Phase W Current, Negative Input					

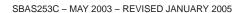


SBAS253C - MAY 2003 - REVISED JANUARY 2005

TQFP Package

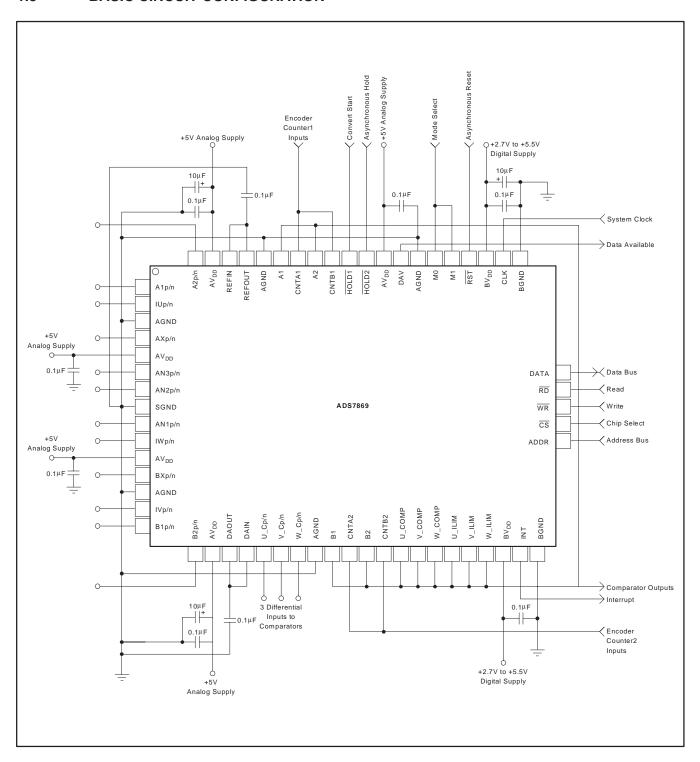
SIGNAL	PIN NUMBER	TYPE	DESCRIPTION
	<u> </u>	Compa	rator Signals of Phase Currents
DAOUT	29	Analog Out	8-Bit DAC Output for Over-Current Limit Value
DAIN	30	Analog In	Over-Current Limit Value as Input for Window Comparators
U_Cp	31	Analog In	Phase U Current Signal Input for Sign and Window Comparator, Positive Input
U_Cn	32	Analog In	Phase U Current Signal Input for Sign and Window Comparator, Negative Input
V_Cp	33	Analog In	Phase V Current Signal Input for Sign and Window Comparator, Positive Input
V_Cn	34	Analog In	Phase V Current Signal Input for Sign and Window Comparator, Negative Input
W_Cp	35	Analog In	Phase W Current Signal Input for Sign and Window Comparator, Positive Input
W_Cn	36	Analog In	Phase W Current Signal Input for Sign and Window Comparator, Negative Input
U_COMP	42	Digital Out	Sign of Phase U Current
V_COMP	43	Digital Out	Sign of Phase V Current
W_COMP	44	Digital Out	Sign of Phase W Current
U_ILIM	45	Digital Out	Over-current Output of Phase U, Active Low Output
V_ILIM	46	Digital Out	Over-current Output of Phase V, Active Low Output
W_ILIM	47	Digital Out	Over-current Output of Phase W, Active Low Output
	1		Other Analog Signals
AN(x)p	15, 12, 10	Analog In	Auxiliary Analog Input Channel (x), Positive Input
AN(x)n	14, 11, 9	Analog In	Auxiliary Analog Input Channel (x), Negative Input
REFIN	97	Analog In	Reference Voltage Input Pin
REFOUT	96	Analog Out	Reference Voltage Output Pin
NC	84, 92, 93, 94	_	No connection (should be left open)
DIGITAL INTER	RFACE SIGNALS		
ADDR(x)	56 – 51	Digital In	Address Decode Input ⁽¹⁾
DATA(xx)	75 – 60	Digital In/Out	Bidirectional 3-state Data Bus ⁽¹⁾
CS	57	Digital In	Active Low Chip-Select Signal ⁽¹⁾
RD	59	Digital In	Active Low Read Signal ⁽¹⁾
WR	58	Digital In	Active Low Write Signal ⁽¹⁾
CLK	77	Digital In	System Clock
INT	49	Digital Out	Active High Interrupt Output
RST	79	Digital In	Active Low Reset Input
M(x)	81, 80	Digital In	Mode Select Pins(1)
DAV	83	Digital Out	Data Available Signal
HOLD1	87	Digital In	Active Low Convert Start and Synchronous Hold Signal for Sample-and-Hold
			Amplifiers
HOLD2	86	Digital In	Active Low Asynchronous Hold Signal for Sample-and-Hold Amplifiers
POWER SUPP	LY		
AV_{DD}	8, 18, 28, 85, 98	Power	Analog Power Supply
BV _{DD}	48, 78	Power	Interface Power Supply
AGND	5, 21, 37, 82, 95		Analog Ground
BGND	50, 76		Interface Ground
SGND	13		Signal Ground

⁽¹⁾ See Digital section for detailed information about the different modes.





1.8 BASIC CIRCUIT CONFIGURATION





1.9 TYPICAL APPLICATION CIRCUIT

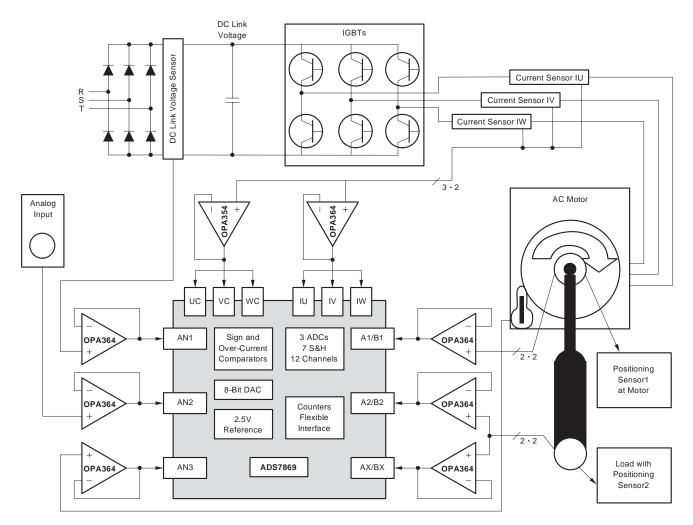


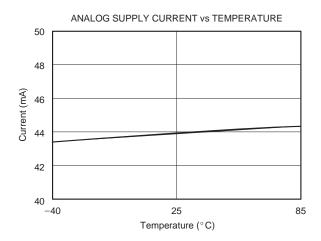
Figure 1-1. Typical Motor Control Application

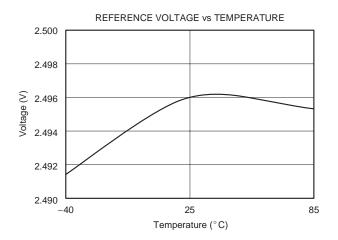
Figure 1–1 shows an example of a typical motor control circuit. The IU, IV and IW channels measure the currents of the motor. The position (speed) of the motor and load are measured simultaneously by A1, B1 and A2, B2, respectively, using resolver or analog encoder sensors. The asynchronous inputs AX and BX can be used to capture the reference signal of encoders to derive the absolute position. Channel AN1 measures the differential DC link voltage. AN3 measures the temperature of the motor. An auxiliary voltage can be measured with channel AN2. The counter inputs connect to the appropriate comparator outputs (A1 to CNTA1, B1 to CNTB1 and so on). The level input of the window comparators, DAIN, should be connected to the 8-bit DAC output DAOUT.

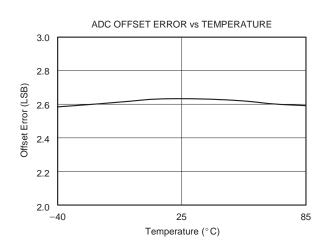


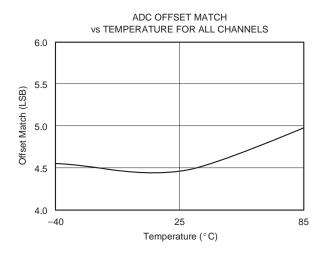
1.10 TYPICAL CHARACTERISTICS

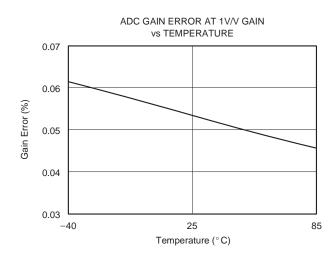
At $T_A = +25$ °C, $AV_{DD} = 5V$, $BV_{DD} = 3.3V$, $V_{REF} = internal +2.5V$, $f_{CLK} = 16MHz$, $f_{SAMPLE} = 1$ MSPS, unless otherwise noted.

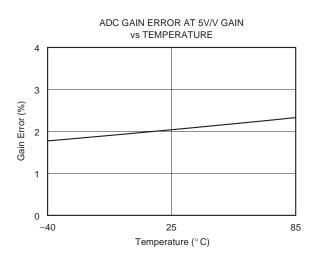










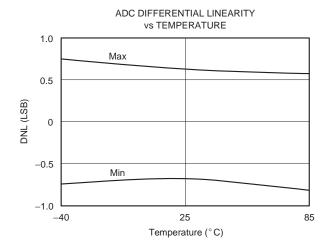


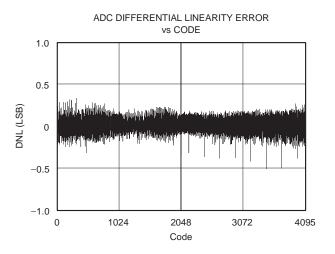


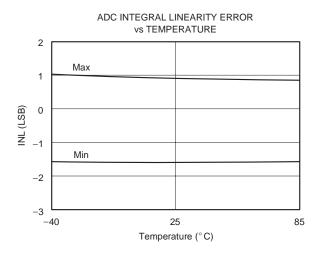
SBAS253C - MAY 2003 - REVISED JANUARY 2005

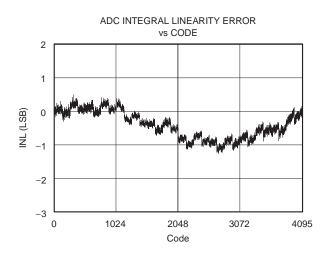
TYPICAL CHARACTERISTICS (Continued)

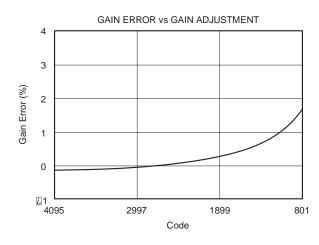
At TA = +25°C, AVDD = 5V, BVDD = 3.3V, VREF = internal +2.5V, fCLK = 16MHz, fSAMPLE = 1 MSPS, unless otherwise noted.

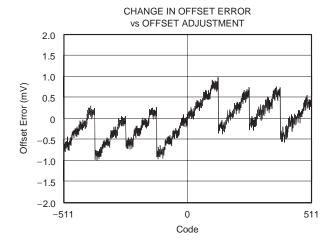








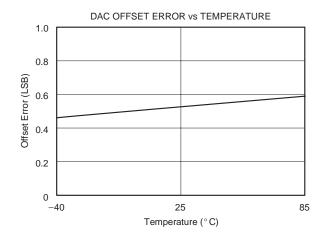


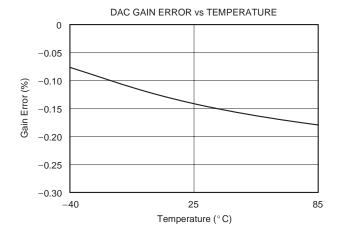


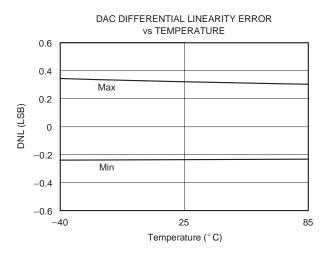


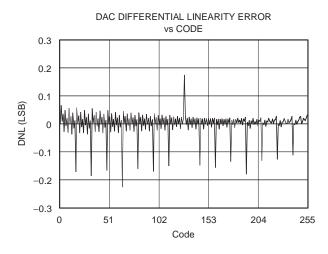
TYPICAL CHARACTERISTICS (Continued)

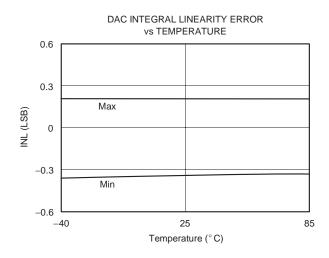
At T_A = +25°C, AV_{DD} = 5V, BV_{DD} = 3.3V, V_{REF} = internal +2.5V, f_{CLK} = 16MHz, f_{SAMPLE} = 1 MSPS, unless otherwise noted.

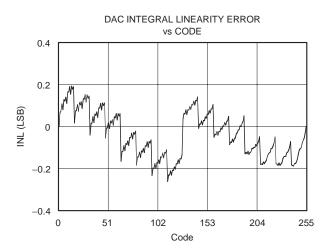










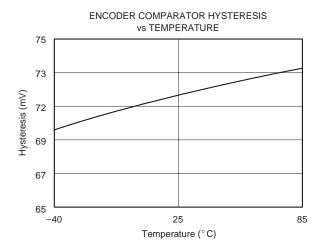


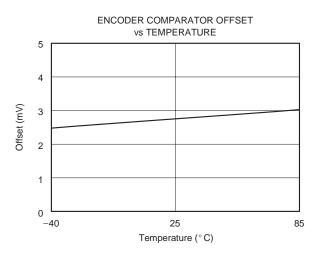


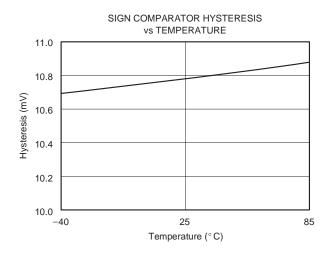
SBAS253C - MAY 2003 - REVISED JANUARY 2005

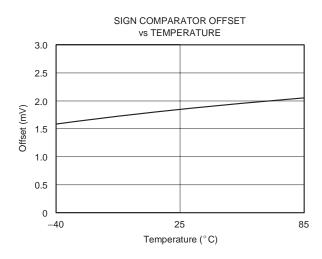
TYPICAL CHARACTERISTICS (Continued)

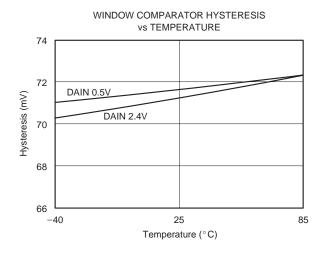
At TA = +25°C, AVDD = 5V, BVDD = 3.3V, VREF = internal +2.5V, fCLK = 16MHz, fSAMPLE = 1 MSPS, unless otherwise noted.

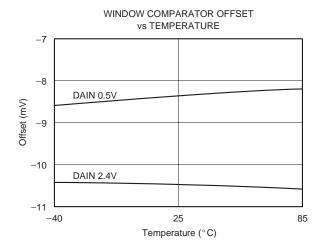














1.11 FUNCTIONAL BLOCK DIAGRAM

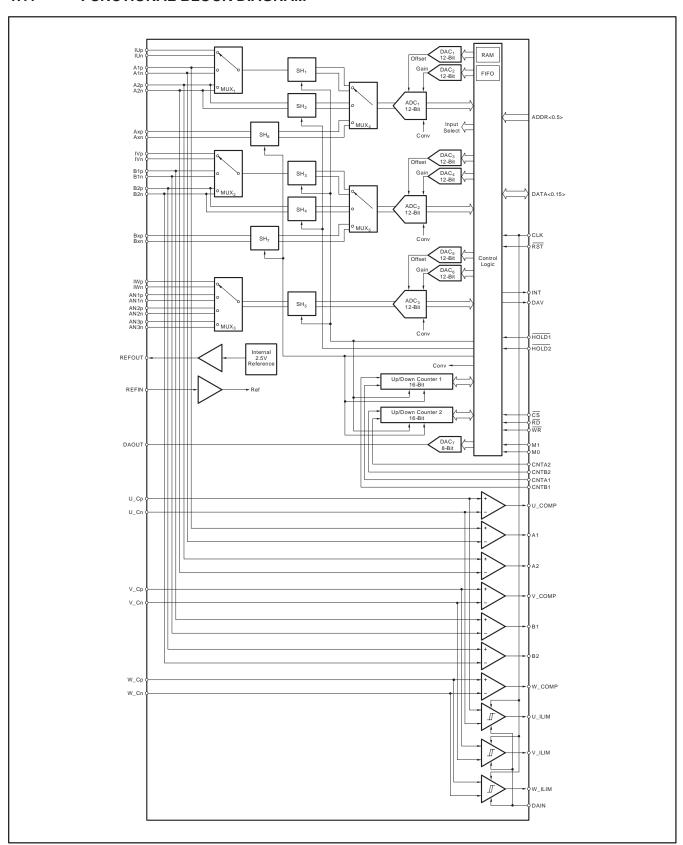


Figure 1-2. Functional Diagram



2 Analog Section

The analog section addresses the Analog-to-Digital Converters, including the gain and offset adjustment. There is also a discussion of the analog inputs, the seven sign comparators, three window comparators, the 8-bit Digital-to-Analog Converter (DAC), the reference voltage, grounding, and the supply voltage.

2.1 Fully Differential Analog Inputs

2.1.1 Analog-to-Digital Converter Inputs

The 12 inputs to the ADCs, as well as the three inputs (U_C, V_C and W_C) to the comparators, are fully differential and provide a good common-mode rejection of 60dB at 50kHz. This is very important to suppress noise in difficult environments.

The seven sample-and-hold circuits from the ADC contain a 5pF capacitor (C_S in Figure 1–3) that is connected via a switch to the analog inputs. Opening the switch holds the data. The switch closes when the conversion is finished. The capacitor is then loaded to an initial voltage that is equal to the reference at the ADC, which is selected with the gain adjustment.

The voltage of the input pin is usually different from the voltage of the sample capacitor when the input switch closes. The sample capacitor needs to be recharged to the 12-bit accuracy, one-half of a least significant bit (LSB), within an acquisition time (t_{AQ}) of at least 200ns.

The minimum –3dB bandwidth of the driving operational amplifier can be calculated to:

$$f_{3db} = \frac{\ln(2) \cdot (n+1)}{2\pi \cdot t_{AQ}}$$
 (1)

where n is equal to 12, the resolution of the ADC (in the case of the ADS7869). When t_{AQ} = 200ns, the minimum bandwidth of the driving amplifier is 7MHz. The bandwidth can be relaxed if the acquisition time is increased by the application.

The OPA364 from Texas Instruments is recommended; besides the necessary bandwidth, it provides a low offset in a small package at a low price.

The phase margin of the driving operational amplifier is usually reduced by the sampling capacitor of the ADC. A resistor between the capacitor and the amplifier reduces this effect; therefore, an internal 300Ω resistor (R_{SER}) is in series with the switch. The resistance of the closed switch (R_{SW}) is approximately 80Ω . See Figure 1–3.

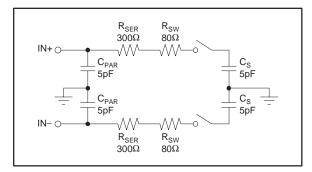


Figure 1-3. Equivalent Input Circuit to the ADCs

The differential input range (positive minus negative input) of the ADC is ±REF_ADC, the reference of the converter, which is selected with the gain adjustment.

It is important that the voltage to all inputs does not exceed more than 0.3V above the analog supply or 0.3V below the ground. There is no DC current flow through the inputs. Current is only necessary when recharging the sample-and-hold capacitors, C_S .

SBAS253C - MAY 2003 - REVISED JANUARY 2005

2.1.2 Window Comparator Inputs

A sampling architecture was selected for the window comparators. The sampling time is two clock cycles with a minimum t_{AQ} (see Equation 1) of 125ns. The necessary accuracy is 10mV (see 8-bit DAC section) with a 5V input range. The required bandwidth of the driving amplifier is 8.8MHz (see Equation 1). The OPAx354 from Texas Instruments is recommended.

The input circuit of the window comparator is similar to the ADC inputs. The only difference is that the sampling capacitors are reduced to 2.5pF. (See Figure 1–4.)

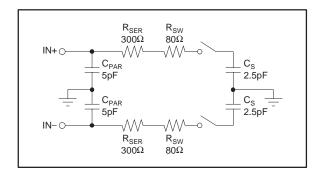


Figure 1-4. Equivalent Input Circuit of the Window Comparators

2.1.3 Sign Comparator Inputs

Four sign comparators are connected to the ADC inputs (A1, B1, A2 and B2); three of the sign comparators are wired to the window comparator inputs (U_C, V_C, and W_C).

The sample capacitors of the ADCs and the window comparators could produce voltage glitches; therefore, it is important to drive the inputs with low impedance.

The lower voltage of the differential input should remain within the range of 0 to AV_{DD} -1.8V.

2.2 Analog-To-Digital Converter

The ADS7869 includes three, SAR-type, 1MSPS, 12-bit ADCs, and three pairs of S/H capacitors, which are each connected to ADC₁ and ADC₂. A single S/H capacitor is connected to ADC₃. Gain and offset adjustments are added to each ADC. (See Figure 1–2 on page 15.)

2.2.1 **HOLD1**, **HOLD2**

The analog inputs are held when the \overline{HOLDx} signals go low. The charges of the synchronous sample-and-holds (S/H₁₋₅) are frozen on the falling edge of $\overline{HOLD1}$. The setup time of $\overline{HOLD1}$, against the rising edge of the system clock, is typically 25ns. The conversion will automatically start on the next rising edge of the clock. The S/Hs are switched back into the sample mode when the conversion is finished, 12 clock cycles later. This point of time is indicated by DAV. (See Figure 1–10 on page 26.) $\overline{HOLD1}$ must go high at the latest at the 13th falling clock after conversion start.

The asynchronous sample and holds (S/H_{6-7}) are triggered by the active low $\overline{HOLD2}$ signal. The setup time of $\overline{HOLD2}$, against the falling edge of $\overline{HOLD1}$, is 0ns; see Figure 1–10. The conversion of these S/H circuits is initiated when they are selected through the digital interface and the $\overline{HOLD1}$ signal goes low. The inputs are connected back to the S/H capacitor when the $\overline{HOLD2}$ signal goes high. $\overline{HOLD2}$ needs to be low during the whole conversion. It is possible to connect $\overline{HOLD1}$ and $\overline{HOLD2}$ together.

TEXAS INSTRUMENTS

SBAS253C - MAY 2003 - REVISED JANUARY 2005

2.2.2 Clock

The ADC uses the external clock CLK, which needs to be in the range of 1MHz to 16MHz. 12 clock cycles are necessary for a conversion, with a minimum of four clock cycles for the acquisition. Therefore, the maximum throughput rate of 1MSPS is achieved with a 16MHz clock and 16 clock cycles per complete conversion cycle. The duty cycle should be 50%; however, the ADS7869 will still function properly with a duty cycle between 30% and 70%.

2.2.3 Reset

A reset condition stops any ongoing conversion and reconnects the synchronous S/Hs to the inputs; see the *Reset* Section.

2.2.4 Gain Adjustment

The output of a 12-bit DAC (REF_ADC) is used as the reference voltage for the ADC. There is one DAC for each ADC. The voltage range is between 0V (code 000_H) and the 2.5V of REFIN (code FFF_H). The ADC operates correctly if the selected voltage is in the range of 0.5V to 2.5V. The output voltage of the DAC sets the differential input range of the ADC, which is \pm REF_ADC. The desired input range can be adjusted in 1.22mV steps.

In the VECANA mode, the gain information contained in the digital input word ADIN automatically sets the DAC value. See the *Vecana Interface* section for further information.

In all other modes, there is a register for every input channel inside the digital interface, which stores the gain information for any given channel. When a particular channel is selected by the application, the value of this register is automatically written to the DAC and the DAC output is adjusted to the desired value. The DAC settles to this value within 250ns (equivalent to the minimum acquisition time).

The gain information inside the registers is set to zero when a reset condition occurs. These registers need to be set to the selected value before the ADCs are used.

In VECANA mode, the DAC is initially set to Full-Scale and the differential input range is equal to \pm (voltage at the REFIN pin).

CAUTION: An essential offset error occurs when data is held on the sampling capacitors A2 and B2 (or AX and BX) and the gain of the ADC is modified in intermediate conversions before converting the particular channels A2 and B2 (or AX and BX). This offset error is possible under two conditions:

- Data can be held on the asynchronous sample-and-hold capacitors AX and BX with the HOLD2 signal.
 Other channels can be converted before the asynchronous signals AX and BX. The offset error occurs if the gain is changed during these conversions.
- 2. With the input commands 4–6, channels A1 and B1 are held together with A2 and B2. Channels A1 and B1 will be converted first. During this conversion or further intermediate conversions, the offset error occurs if the gain is modified before the conversion of channels A2 and B2.

2.2.5 Offset Adjustment

The offset can be adjusted, similar to the gain, to a 12-bit level with respect to the actual input voltage range of the ADC. For example, if the input range is ± 1 V, the offset can be adjusted in increments of 488μ V. The maximum adjustment is $\pm 12.5\%$ of the input range.

There is a register inside the digital interface for each input channel. This registers store the offset adjustment value for each channel. When a channel is selected for conversion, the offset is automatically adjusted. The selected channel and the related register information must not be changed during the conversion.

Setting the register to 201_H results in a -12.5% adjustment, 000_H results in no adjustment, and $1FF_H$ results in a +12.5% adjustment. The offset adjustment value 200_H is not allowed.

The offset adjustment cannot be used in VECANA mode. A reset condition will set the offset adjustment to zero.



2.2.6 Transition Noise

The transition noise of the ADS7869 itself is low, as shown in Figure 1–5. Applying a low-noise DC input and initiating 8000 conversions generated this histogram.

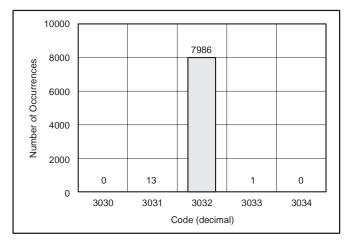


Figure 1-5. Histogram of 8000 Conversions

2.3 Sign Comparators

The ADS7869 includes two sets of sign comparators that differ in their hysteresis. The first set, which is used for the position sensor inputs in motor control applications, is connected to the inputs A1, B1, A2, and B2. The hysteresis of these comparators is typically 75mV. In motor control applications, these comparators are used to measure the signs of the position sensor input signals.

The second set is in parallel to the window comparators at the U_C, V_C, and W_C pins. The hysteresis of these components is typically 10mV. In motor control applications, these comparators are used to measure the sign of the main currents.

The sign comparator switches from 0 to 1 if the differential input voltage is above +1/2 of the hysteresis. If the output is 1, the sign comparator switches back to 0 if the differential input voltage is below -1/2 of the hysteresis. See Figure 1–6.

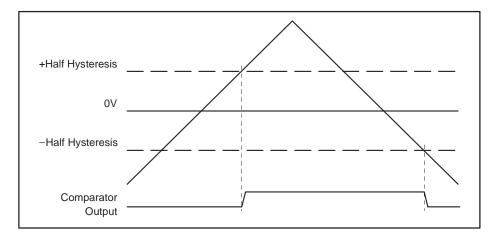


Figure 1-6. Typical Transfer Function of a Sign Comparator



SBAS253C - MAY 2003 - REVISED JANUARY 2005

The input range of the comparators is limited. The lower voltage of the differential inputs should always be within the range of 0 to $AV_{DD}-1.8V$.

On every comparator, the output is delayed to the input voltage. This delay is dependent on the overdrive of the comparator inputs. The overdrive is the input voltage (V_{IN}) minus one-half of the hysteresis.

If the differential input voltage of the position sensor sign comparator is switching from –40mV to +40mV (step function, 2.5mV overdrive), then the delay time of the output is typically 100ns. The delay is reduced to typically 25ns if the comparator is switching between –100mV and +100mV (72.5mV overdrive). For the delay times as a function of step size with different overdrives, see Figure 1–7 and Figure 1–8.

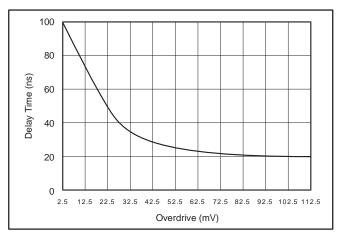


Figure 1–7. Position Sensor Comparator Overdrive

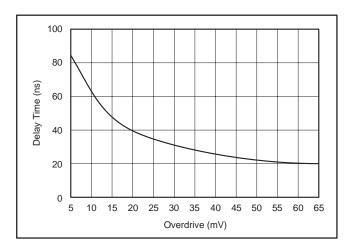


Figure 1-8. Current Sign Comparator Overdrive



SBAS253C - MAY 2003 - REVISED JANUARY 2005

2.4 Window Comparators

The window comparators test if the input voltage is within a certain range; this range is \pm (voltage applied to DAIN, pin 30). If the differential input voltage remains within this range, then the output of the window comparator is 1. If the voltage is outside this range, then the output is set to 0. The window comparator has a hysteresis that is turned on when the output is 0. The comparator outputs switch back to 1 when the input voltage is within in the range of \pm (DAIN -60mV). (See Figure 1-9.) The voltage at DAIN needs to be in a range of 0.5V to 2.5V.

The window comparator has a switched capacitor circuitry, similar to the ADC architecture, but different from other window comparators. This design dramatically increases the accuracy; due to the additional accuracy, a proper front-end of the input signal is required. (See the *Window Comparator Inputs* section.)

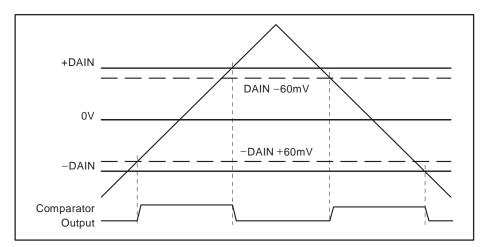


Figure 1-9. Typical Transfer Function of a Window Comparator

Two clock cycles are used to sample the inputs. The next two clock cycles are used to test the lower and the upper voltage limit. Every four clock cycles (or every 250ns with a 16MHz clock) the output of the window comparator is updated. In a worst-case scenario, it takes six clock cycles for the window comparator to detect a current limit. The window comparators need a continuous clock to operate properly.

In motor control applications, the window comparators are used to monitor the main currents for failures.

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SBAS253C - MAY 2003 - REVISED JANUARY 2005

2.5 8-Bit Digital-to-Analog Converter

A voltage between 0.5V to 2.5V is required at DAIN (pin 30) to set the range of the window comparators; this can be accomplished with the 8-bit DAC. The DAC value is programmed via the digital interface. Input code 00_H corresponds to a DAC output voltage of 0V. The full-scale value (FF_H) is at 2.49V (internal reference minus 1LSB).

The impedance of the output is typically $10k\Omega$; the output impedance is independent of the output voltage. The DAC output is connected to DAOUT (pin 29). The settling time (t_S) is dependent on the external capacitance (C_P) on this pin, and can be calculated to:

$$t_s = 10k\Omega \cdot C_e \cdot (n+1) \cdot ln(2)$$
 (2)

In this equation, n is equal to 8, the resolution of the DAC. The output impedance also limits the output current. This current should not exceed $0.5\mu A \cdot 10k\Omega = 5mV$).

DAOUT and DAIN can be shorted. A capacitor (typically $0.1\mu F$) can be used to low-pass the DAC output; however, this low-pass configuration is not required.

2.6 Internal Reference

The internal reference, REFOUT (pin 96), provides the 2.5V required for the reference input of the ADCs at REFIN (pin 97). An internal buffer with a high impedance output drives the reference output pin. This internal buffer is optimized to reject glitches at the reference pin. Any capacitor can be connected to the REFOUT pin in able to reduce noise. It is recommended that a 0.1µF capacitor be connected between the REFOUT (pin 96) and the SGND (pin 13). The Signal ground, SGND, is used internally as a negative reference. The reference voltage is considered a differential voltage between this ground and REFOUT.

Normally, the REFOUT and REFIN pins are both shorted. The internal reference provides an excellent temperature drift, typically 20ppm, and an initial accuracy of 2.5V±20mV at 25°C. If this does not provide the required accuracy for an application, then an external reference can be connected to the REFIN pin.

2.7 Grounding

Optimal test results were achieved with a solid ground plane: linearity, offset, and noise performance each showed improvement. During PCB layout, care should be taken that the return currents do not cross any sensitive areas or signals.

Digital signals that interface with the ADS7869 are referenced to the solid ground plane. ESD protection diodes, inside the ADS7869, start conducting if the grounds are separated and the digital inputs go below –0.3V; this includes short glitches. Current will flow through the substrate of the ADS7869 and will disturb the analog performance.

2.8 Supply

The ADS7869 has two separate supplies, BV_{DD} (pins 48 and 78) and AV_{DD} (pins 8, 18, 28, 85 and 98).

 BV_{DD} is used as a digital pad supply only, and is in the range of 2.7V to 5.5V. This allows the ADS7869 to interface with all state-of-the-art processors and controllers. BV_{DD} should be filtered in order to limit the noise energy from the external digital circuitry to the ADS7869. The current through BV_{DD} is far below 5mA; depending on the external load, a 10Ω to 100Ω resistor can be placed between the external digital circuitry and the ADS7869. Bypass capacitors (two $0.1\mu F$ and one $10\mu F$) should be placed between the two BV_{DD} pins and the ground plane.

 AV_{DD} supplies the internal circuitry, and can vary from 4.5 to 5.5V. It is not possible to use a passive filter between the digital board supply of the application and the AV_{DD} pins, because the supply current of the ADS7869 is typically 45mA. In order to generate the analog supply voltage for the ADS7869 and the necessary analog front-end, a linear regulator (7805 family) is recommended. Bypass capacitors of $0.1\mu F$ should be placed between all AV_{DD} pins and the ground plane. Bypass capacitors of $10\mu F$ should be placed between two AV_{DD} pins and the ground plane.

SBAS253C - MAY 2003 - REVISED JANUARY 2005

3 **Digital Section**

3.1 Introduction

The ADS7869 can interface with a DSP or μC in four different ways. The M1 and M0 pins determine in which mode the ADS7869 will communicate; see Table 1-1. It can be connected as a standard VECANA01 interface, as an SPI, or as two different parallel interfaces.

Table 1-1. Selection of Interface Mode

M1	MO	MODE
0	0	VECANA mode
0	1	SPI mode
1	0	Parallel 1
1	1	Parallel 2

As a function of the selected mode, some pins will have different assignment as shown in Table 1–2.

Table 1-2. Mode vs Pin Functions

Pin No.	VECANA Mode(1)	SPI ⁽¹⁾	Parallel 1	Parallel 2
80, 81 (M1, M0)	00	01	10	11
56	NC	NC	ADDR0 (LSB)	ADDR0 (LSB)
55	NC	NC	ADDR1	ADDR1
54	NC	NC	ADDR2	ADDR2
53	S1	NC	ADDR3	ADDR3
52	S0	NC	ADDR4	ADDR4
51	WINCLK	NC	ADDR5 (MSB)	ADDR5 (MSB)
75	NC	NC	DATA0 (LSB)	DATA0 (LSB)
74	NC	NC	DATA1	DATA1
73	NC	NC	DATA2	DATA2
72	NC	NC	DATA3	DATA3
71	NC	NC	DATA4	DATA4
70	ADOUT1 ADOUT1 ⁽³⁾	NC	DATA5	DATA5
69	ADOUT2 ADOUT2 ⁽³⁾	NC	DATA6	DATA6
68	ADOUT3 ADOUT3 ⁽³⁾	SPISOMI	DATA7	DATA7
67	ADIN ADIN ⁽³⁾	SPISIMO	DATA8	DATA8
66	NC	SPICLK	DATA9	DATA9
65	NC	NC	DATA10	DATA10
64	NC	NC	DATA11	DATA11
63	NC	NC	DATA12	DATA12
62	NC	NC	DATA13	DATA13
61	NC	NC	DATA14	DATA14
60	NC	NC	DATA15 (MSB)	DATA15 (MSB)
57	NC	SPISTE	CS	CS
59	NC	NC	R/W	RD / – (2)
58	NC	NC	WE	WR / R/W (2)
77	CLK ADCLK(3)	CLK	CLK	CLK
79	RST	RST	RST	RST
49	NC	INT	INT	INT
83	DAV ADBUSY(3)	DAV	DAV	DAV
87	HOLD1 ADCONV(3)	HOLD1	HOLD1	HOLD1
86	HOLD2 NPSH(3)	HOLD2	HOLD2	HOLD2

⁽¹⁾ NC means no connection. The NC pins in VECANA01 and SPI modes should be grounded with a pull-down resistor.

⁽²⁾ For parallel mode 11 there is one sub-mode for compatibility with the TMS320c54xx DSP family; see Mode 11 Bus Access (TMS320c54xx DSP family-compatible mode) section.

⁽³⁾ Original VECANA01 pin names.



SBAS253C - MAY 2003 - REVISED JANUARY 2005

3.2 VECANA Interface

The VECANA01 mode of the ADS7869 interface acts exactly like the original VECANA01 interface. This mode was added to the ADS7869 for backward-compatibility purposes. The VECANA01 interface is a proprietary serial interface with one serial input and three serial outputs.

Sampling and conversion are controlled with the HOLD1 and CLK inputs. The ADS7869 is designed to operate with an external clock supplied to the CLK input. This allows the conversion to be synchronous with the system clock, thus reducing transient noise effects. The DAV signal indicates when a conversion is taking place with a low-level pulse. The DAV signal is equivalent to the ADBUSY signal in the VECANA01.

The typical clock frequency for the specified accuracy is 16MHz. This results in a complete conversion cycle, S/H acquisition and analog-to-digital (A/D) conversion of $1\mu s$. It is possible to stop the clock after 14 clock cycles and start it again when the next conversion starts (after HOLD1 goes low); see the *WINCLK Selection* section.

When power is applied to the ADS7869, one conversion cycle is required for initialization before valid digital data is transmitted on the second cycle. The first conversion after power is applied is performed with indeterminate configuration values in the Input Setup Register. The second conversion uses those values to perform proper conversions and to output valid digital data from each of the ADCs.

The setup word received by the ADS7869 is used for the next conversion cycle while the ADCs are converting and transmitting their serial digital data for one conversion cycle. The 13-bit word is supplied to ADIN (pin 67), and is stored in the buffered Input Setup Register.

Configuration parameters are:

- DAC output voltage;
- Programmable gain/input voltage range;
- Input multiplexer; and
- sample-and-hold selection.

The DAC Input portion of the ADIN word (bits DAC [7...0]) determines the value of the DAC output voltage; see Table 1–5. The 8-bit DAC has 256 possible output steps from 0V to +2.490V. The value of 1LSB is 9.76mV (see Table 1–3 for input/output relationships).

Table 1–3 to Table 1–6 show information regarding these parameters.

Table 1–3. DAC Input/Output Relationships

DAC Inp	DAC Input Code					
00H	000 0000 _B					
01 _H	0000 0001 _B	+0.010V				
	::					
	:					
FF _H	1111 1111 _B	+2.490V				

Table 1-4. VECANA Gain Select Information

Gain Select Bits	Gain Setting	Input Voltage Range
⁰ H	5.0V/V	±0.5V
1 _H	2.5V/V	±1.0V
² H	1.25V/V	±2.0V
³ H	1.0V/V	±2.5V



SBAS253C - MAY 2003 - REVISED JANUARY 2005

The Gain Select portion (bits GAIN [1..0]) determines the programmable gain of the ADIN word; see Table 1–5. The gain for all three ADCs is set by one gain input parameter. The gain values and allowable full-scale inputs are shown in Table 1–4.

The gain setting and input voltage range for the channels AN1, AN2, and AN3 at ADC3 are always 1.0V/V with respect to $\pm 2.5V$.

Table 1-5. 13-bit VECANA ADIN Word Format

D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
DAC7	DAC6	DAC5	DAC4	DAC3	DAC2	DAC1	DAC0	GAIN1	GAIN0	IN2	IN1	IN0

3.2.1 Input Channel Selection

Table 1–6 shows the relationships between the value of the input select bits and the input channels that are converted.

Table 1–6. Controls for Input Multiplexers and Sample Holds

INPUT SELE	INPUT SELECT, BITS 2-0				ANALOG SIGNAL CONNECTED TO ADCX								
HEX CODE	BINARY CODE	ΑI	C ₁	AD	C ₂	ADC ₃							
0H	000	_	_	_	_	AN3	SH ₅						
¹ H	001	AX	SH ₆	BX	SH ₇	AN3	SH ₅						
2 _H	010	A2	SH ₁	B2	SH ₃	AN2	SH ₅						
3 _H	011	A2	SH ₂	B2	SH ₄	AN2	SH ₅						
4H	100	A1	SH ₁	B1	SH ₃	AN1	SH ₅						
5 _H	101	A1	SH ₁	B1	SH ₃	AN1	SH ₅						
6H	110	A1	SH ₁	B1	SH ₃	AN1	SH ₅						
7 _H	111	IU	SH ₁	IV	SH ₃	IW	SH ₅						

Input Select = 0H

The synchronous sample-and-hold, SH₅, samples AN3 (only), then ADC3 converts it on the signal HOLD1.

Input Select = 1_H

AX is sampled by the asynchronous sample-and-hold, $SH_{6,}$ with the signal $\overline{HOLD2}$; ADC1 converts it on the signal $\overline{HOLD1}$. BX is sampled by the asynchronous sample-and-hold, $SH_{7,}$ with the signal $\overline{HOLD2}$; ADC2 converts it on the signal $\overline{HOLD1}$. AN3 is sampled by the synchronous sample-and-hold, $SH_{5,}$ then ADC3 converts it on the signal $\overline{HOLD1}$.

The signal $\overline{HOLD2}$ must be low during the entire conversion. If $\overline{HOLD2}$ is high before a conversion starts, ADC₁ and ADC₂ will not convert.

Input Select = 2_H

A2 is sampled by the synchronous sample-and-hold, SH_1 ; ADC_1 converts it on the signal HOLD1. B2 is sampled by the synchronous sample-and-hold, SH_3 ; ADC_2 converts it on the signal $\overline{HOLD1}$. AN2 is sampled by the synchronous sample-and-hold, SH_5 ; ADC_3 converts it on the signal $\overline{HOLD1}$.

Input Select = 3_H

A2 is converted by ADC_1 on the signal $\overline{HOLD1}$. A2 is sampled on SH_2 in a preceding conversion with Input Select 4_H , 5_H , or 6_H . B2 is converted by ADC_2 on the signal $\overline{HOLD1}$. B2 is sampled on SH_4 in a preceding conversion with Input Select 4_H , 5_H , or 6_H . AN2 is sampled by the synchronous sample-and-hold, SH_5 ; ADC_3 converts it on the signal $\overline{HOLD1}$.

Input Select = 4_H , 5_H and 6_H

A1 is sampled by the synchronous sample-and-hold, SH_1 ; ADC_1 converts it on the signal $\overline{HOLD1}$. B1 is sampled by the synchronous sample-and-hold, SH_3 ; ADC_2 converts it on the signal $\overline{HOLD1}$. AN1 is sampled by the synchronous sample-and-hold, SH_5 ; ADC_3 converts it on the signal $\overline{HOLD1}$. A2 is sampled by the synchronous sample-and-hold, SH_2 , on the signal $\overline{HOLD1}$. B2 is sampled by the synchronous sample-and-hold, SH_4 , on the signal $\overline{HOLD1}$.



SBAS253C - MAY 2003 - REVISED JANUARY 2005

Input Select = 7_H

IU is sampled by the synchronous sample-and-hold, SH_1 ; ADC_1 converts it on the signal $\overline{HOLD1}$. IV is sampled by the synchronous sample-and-hold, SH_3 ; ADC_2 converts it on the signal $\overline{HOLD1}$. IW is sampled by the synchronous sample-and-hold, SH_5 ; ADC_3 converts it on the signal $\overline{HOLD1}$.

3.2.2 **VECANA Timing Characteristics**(1)

Over recommended operating free-air temperature range at -40°C to +85°C, AV_{DD} = 5V, BV_{DD} = 3V - 5V.

PARAMETER	SYMBOL	MIN	MAX	UNIT
ADCLK Period	t _{C1}	62.5		ns
ADCLK HIGH or LOW Time	t _{W1}	20		ns
HOLD1 Signal Setup Time	t _{SU1}	25		ns
HOLD1 Signal Hold Time	t _{H1}	20	15 + 12.5t _{C1}	ns
HOLD2 Signal Setup Time	t _{SU2}	0		ns
HOLD2 Signal Hold Time	t _{H2}	0		ns
Delay Time from ADCLK Rising to DAV Falling Edge	t _{D1}		15	ns
Output Data Delay Time	t _{D2}		10	ns
Input Data Setup Time	t _{SU3}	10		ns
Input Data Hold Time	t _{H3}	10		ns
Delay Time from ADCLK Rising to DAV Rising Edge	t _{D3}		15	ns
Sampling Time	t _{SAMPLE}	4		t _{C1}

(1) All input signals are specified with t_R = t_F = 5ns (10% to 90% of BV_{DD}) and timed from a voltage level of (V_{IL} + V_{IH})/2.

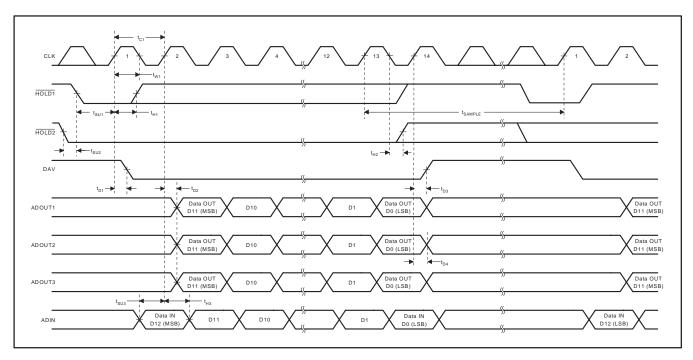


Figure 1-10. VECANA Access



3.2.3 WINCLK Selection

It is possible to apply a separate clock for the window comparators at the WINCLK (pin 51) in VECANA01 mode. By using the pins S0 (pin 52) and S1 (pin 53) as decoder inputs, the window comparators can be supplied with the system clock, an external clock (supplied by the WINCLK), and two divided external clocks; see Table 1–7.

Table 1–7. Window Comparator Clock

S 1	S0	Clock to Window Comparators
0	0	Synchronous system clock
0	1	External WINCLK clock
1	0	External WINCLK clock / 2
1	1	External WINCLK clock / 4

The system clock, provided by CLK (pin 77), drives the window comparators in the other modes (SPI and parallel modes).

The window comparator clock, WINCLK, must be synchronous with the system clock, provided by CLK (pin 77). The window comparators can be supplied with a 6MHz clock when the system runs with a 15MHz clock.

In order to provide the window comparators with a maximum of 1µs detection time, a minimum clock of 6MHz must be supplied. See the *Window Comparator* section. It is necessary to operate the window comparators with a continuous clock.

3.3 Serial Peripheral Interface (SPI)

The SPI runs fully asynchronous to the rest of the system. The four signals of the SPI are SPICLK, SPISIMO, SPISOMI and SPISTE. The maximum speed of the SPI is 25MHz. When the select signal SPISTE is HIGH, the entire SPI, except the address and the data registers, is in reset state. The SPI clock SPICLK and the serial data input SPISIMO are disabled when SPISTE is HIGH. The incoming data is strobed by the SPI on the falling edge of the SPICLK. Outgoing data is put on the output SPISOMI on the rising edge of the SPICLK (see Figure 1–11). For a transmission of one 16-bit data word, 24 bits are required. The first incoming bit to the ADS7869 determines if the whole transmission is a read or a write operation. A '1' means a read and a '0' means a write operation. There are seven address bits, but only the six LSBs are used. Then the 16 data bits are transmitted or received (see Table 1–8).

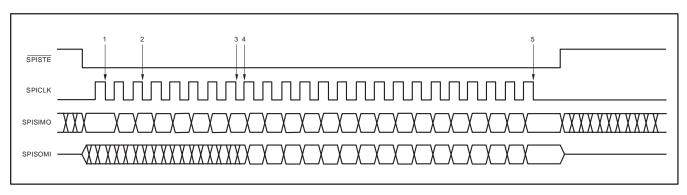


Figure 1-11. One SPI Transfer Cycle

Table 1-8. SPI Write 24-bit Word Format

A23	A22	A21	A20	A19	A18	A17	A16	A15	A14	A13	A12	A11	A10	A9	A8	A7	A6	A5	A4	A3	A2	A1	A0
R/W	Χ			Add	ress										Data								



SBAS253C - MAY 2003 - REVISED JANUARY 2005

One 16-bit transfer is accomplished, as follows:

- 1. On the first falling edge of SPICLK, the read/write bit is strobed.
- 2. On the third falling edge of SPICLK, the MSB of the address (bit 5) is strobed.
- 3. On the eighth falling edge of SPICLK, the LSB of the address (bit 0) is strobed and the corresponding data of the register map is read.
- 4. On the ninth rising edge, the data read from the register map is latched into a shift register and shifted one position each rising edge of the SPICLK. This data is always sent out, even when a write operation is performed.
- 5. On the 24th falling edge of SPICLK, the last data bit is shifted in from SPISIMO and a write pulse is generated to write the data into the register map, if a write operation was performed.

During continuous read or write (see Figure 1–12), the address is decrementing after each read or write; see the indicating arrows. When the address is set to 00_H, in the beginning, the FIFO can be read out fast. The data is written into the register map on the 16th SPICLK of a data word. If the SPISTE is inactive before the 16th SPICLK in a data word, the data is not written into the register map; therefore, the data is lost.

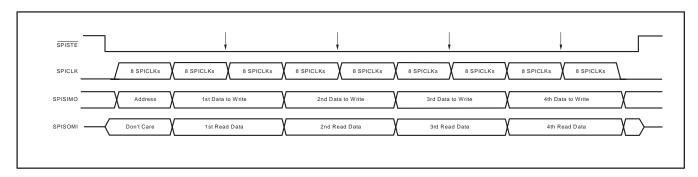


Figure 1-12. Continuous SPI Transfer Cycle

SBAS253C - MAY 2003 - REVISED JANUARY 2005

3.3.1 SPI Timing Characteristics⁽¹⁾

Over recommended operating free-air temperature range at -40° C to $+85^{\circ}$ C, $AV_{DD} = 5V$, $BV_{DD} = 3V - 5V$.

PARAMETER	SYMBOL	MIN	MAX	UNIT
SPICLK Period	t _{C1}	40		ns
SPICLK HIGH or LOW Time	t _{W1}	10		ns
Delay Time from SPISTE Falling to SPICLK Rising Edge	t _{D1}	15		ns
Delay Time from SPISTE Falling to SPISOMI not Tristate	t _{D2}		15	ns
Data Setup Time	t _{SU1}	10		ns
Input Data Hold Time	t _{H1}	10		ns
Output Data Delay Time	t _{D3}		10	ns
Enable Lag Time	t _{D4}	15		ns
SPISOMI Disable Time	t _{D5}		15	ns
Sequential Transfer Delay	t _{W2}	30		ns

(1) All input signals are specified with $t_R = t_F = 5$ ns (10% to 90% of BV_{DD}) and timed from a voltage level of (V_{II} + V_{IH})/2.

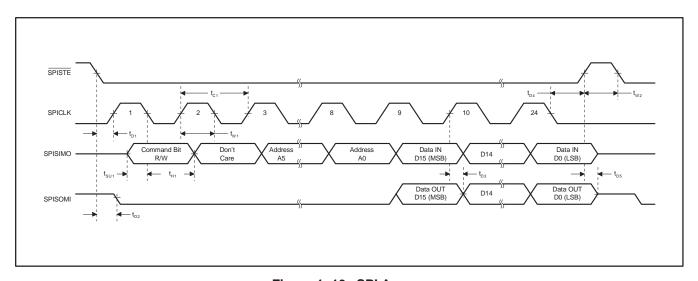


Figure 1-13. SPI Access



SBAS253C - MAY 2003 - REVISED JANUARY 2005

3.4 Parallel Interface

The Parallel Interface has the following major capabilities:

- 1. Data words:
 - Data path with a width of 16 bits is supported.
- 2. Bus handshaking:
 - Separate RD and WR style control signals.
 - Separate R/W and WE style control signals.
- 3. Mapping
 - The ADS7869 appears as a memory-mapped peripheral. See Table 1–10 on page 37 and Table 1–11 on page 38.
 - Internal registers are directly mapped into consecutive locations in the external bus address space.

3.4.1 Parallel Read and Write Control

Reading from and writing to the ADS7869 is controlled by the chip select input $(\overline{CS}, pin 57)$, the write input $(\overline{WR}, pin 58)$ and the read input $(\overline{RD}, pin 59)$. There is a control bit for mode 11, which can be reset to activate a special compatibility mode. (See *Mode 11 Bus Access [DSP-compatible mode]* section.) The read and write pins can be configured as a combined Read/Write and Write enable depending on the needs of the host processor. The mode pins M0 and M1 determine the method by which the ADS7869 is accessed by the host (see Table 1–9).

Table 1-9. Host Parallel Port Operation

[M1, M0]	PIN NAME	PIN NO.	FUNCTION	OPERATION
,10'	R/W	59	Read/Write Signal	0: Data can be written to ADS7869; see WE 1: Data from ADS7869 is written to the Data Bus
	WE	58	Write Enable	0: Data Bus is read by ADS7869 at rising edge 1: ADS7869 Write function is disabled
,11' standard	RD	59	Read Signal	0: Data from ADS7869 is written to the Data Bus 1: ADS7869 Read function is disabled
	WR	58	Write Signal	0: Data Bus is read by ADS7869 at rising edge 1: ADS7869 Write function is disabled
,11' TMS	_	59	_	Signal is ignored by ADS7869
	R/W	58	Read/Write Signal	0: Data Bus is read by ADS7869 at rising edge of CS 1: Data from ADS7869 is written to the Data Bus



3.4.2 Mode 10 Bus Access

When M1 = 1 and M0 = 0 (mode 10), the host port uses the \overline{RD} (pin 59) as a read/write signal (R/ \overline{W}) and the \overline{WR} (pin 58) as a write-enable signal \overline{WE} . The current cycle is only processed when the chip select input \overline{CS} (pin 57) of the ADS7869 is active low.

 R/\overline{W} determines the direction of the transfer during a bus cycle; see Figure 1–14. When R/\overline{W} is high, data is placed on the databus by ADS7869, according to the address, as long as \overline{CS} is low.

For a write cycle, a low-level signal (on $\overline{\text{WE}}$) indicates to the ADS7869 that the data on the bus is valid. With the rising edge of $\overline{\text{WE}}$ the data is latched into the ADS7869. When the host sets $\overline{\text{CS}}$ to low, a valid access to the ADS7869 is detected (see Figure 1–15).

3.4.2.1 Read Timing Characteristics(1)

Over recommended operating free-air temperature range at -40°C to +85°C, AV_{DD} = 5V, BV_{DD} = 3V - 5V.

PARAMETER	SYMBOL	MIN	MAX	UNIT
Delay time from CS LOW to output data not in tri-state mode(2)	t _{D1}		8	ns
Access time from address valid to output data valid	t _{A1}		10	ns
Delay time from address not valid to output data not valid ⁽³⁾	t _{D2}	0	8	ns
Delay time from CS HIGH to output data in tri-state mode ⁽⁴⁾	t _{D3}		8	ns

- (1) All input signals are specified with t_R = t_F = 5ns (10% to 90% of BV_{DD}) and timed from a voltage level of (V_{IL} + V_{IH})/2.
- (2) Refer to CS signal or R/W signal whichever occurs last.
- (3) One or more read cycles can be performed in one $\overline{\text{CS}}$ cycle.
- (4) Refer to CS signal or R/W signal whichever occurs first.

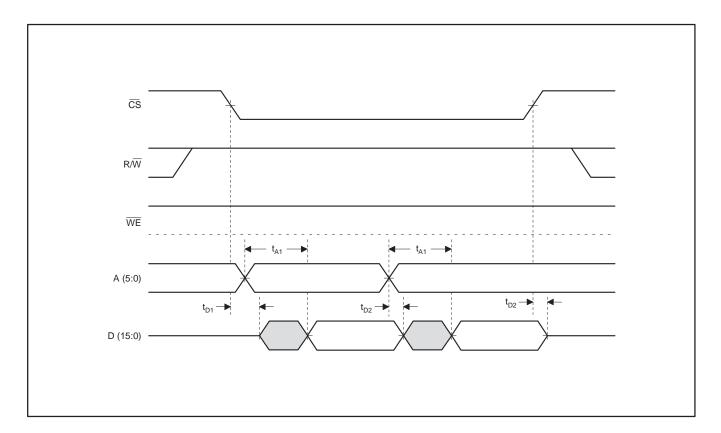


Figure 1–14. Mode 10 Read Access



SBAS253C - MAY 2003 - REVISED JANUARY 2005

3.4.2.2 Write Timing Characteristics⁽¹⁾

Over recommended operating free-air temperature range at -40° C to $+85^{\circ}$ C, $AV_{DD} = 5V$, $BV_{DD} = 3V - 5V$.

PARAMETER	SYMBOL	MIN	MAX	UNIT
Delay time from R/W LOW to CS LOW	t _{D1}	0		ns
Access time from CS LOW to WE HIGH	t _{A1}	25		ns
Width time for WE LOW	t _{W1}	20		ns
Width time for WE HIGH ⁽²⁾	t _{W2}	10		ns
Setup time, address valid before rising edge of WE	t _{SU1}	10		ns
Hold time, address valid after rising edge of WE	t _{H1}	5		ns
Setup time, data valid before rising edge of WE	t _{SU2}	10		ns
Hold time, data valid after rising edge of WE	t _{H2}	5		ns
Delay time from WE HIGH to CS HIGH	t _{D2}	10		ns
Delay time from CS HIGH to R/W HIGH	t _{D3}	0		ns

- (1) All input signals are specified with $t_R = t_F = 5$ ns ($10\frac{\%}{10}$ to 90% of BVDD) and timed from a voltage level of ($V_{IL} + V_{IH}$)/2.
- (2) One or more write cycles can be performed in one $\overline{\text{CS}}$ cycle.

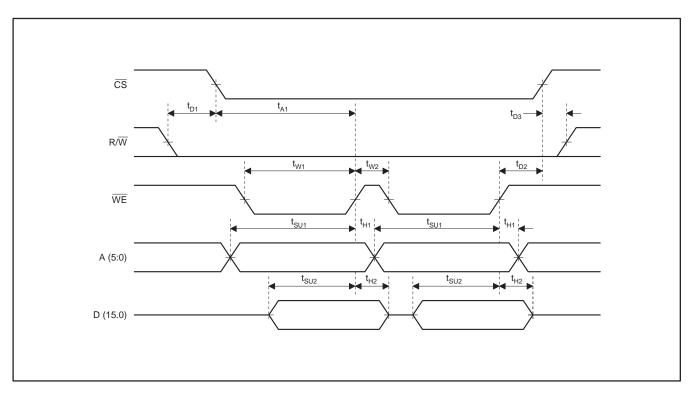


Figure 1-15. Mode 10 Write Access



3.4.3 Mode 11 Bus Access (Standard Mode)

When M1 = 1 and M0 = 1 (mode 11), the host port uses \overline{WR} (pin 58) and \overline{RD} (pin 59) for independent write and read access to the ADS7869. The current cycle is processed only when the \overline{CS} (pin 57) input of the ADS7869 is an active low. Bit 0 of the PARALLEL register (Address 27_H) must have a reset value of 1 to use the standard mode.

In Mode 11 operation, \overline{RD} indicates to the ADS7869 that the host processor has requested a data transfer (see Figure 1–16). The ADS7869 outputs data to the host. The address can be changed within a \overline{CS} low cycle, and more than one data can be read.

To configure the registers in the ADS7869, the host issues a $\overline{\text{WR}}$ signal to indicate that valid data is available on the bus. With the rising edge of the $\overline{\text{WR}}$ the data is latched into the ADS7869; see Figure 1–17. The address for the ADS7869 must be valid before the write operation takes place. The $\overline{\text{CS}}$ signal can stay low between two consecutive writes.

3.4.3.1 Read Timing Characteristics⁽¹⁾

Over recommended operating free-air temperature range at -40°C to +85°C, AV_{DD} = 5V, BV_{DD} = 3V - 5V.

PARAMETER	SYMBOL	MIN	MAX	UNIT
Delay time from CS LOW to output data not in tri-state mode ⁽²⁾	t _{D1}		8	ns
Access time from address valid to output data valid	t _{A1}		10	ns
Delay time from address not valid to output data not valid(3)	t _{D2}	0	8	ns
Delay time from CS HIGH to output data in tri-state mode ⁽⁴⁾	t _{D3}		8	ns

- (1) All input signals are specified with t_R = t_F = 5ns (10% to 90% of BV_{DD}) and timed from a voltage level of (V_{IL} + V_{IH})/2.
- (2) Refer to CS signal or RD signal whichever occurs last.
- (3) One or more read cycles can be performed in one CS cycle.
- (4) Refer to $\overline{\text{CS}}$ signal or $\overline{\text{RD}}$ signal whichever occurs first.

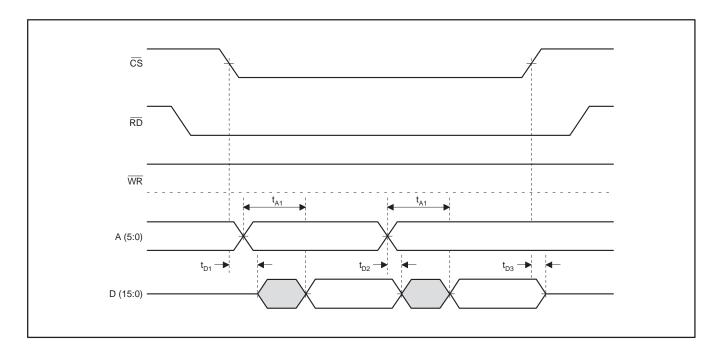


Figure 1–16. Mode 11 Read Access (Standard Mode)



SBAS253C - MAY 2003 - REVISED JANUARY 2005

3.4.3.2 Write Timing Characteristics⁽¹⁾

Over recommended operating free-air temperature range at -40° C to $+85^{\circ}$ C, $AV_{DD} = 5V$, $BV_{DD} = 3V - 5V$.

PARAMETER	SYMBOL	MIN	MAX	UNIT
Access time from CS LOW to WR HIGH	t _{A1}	15		ns
Width time for WR LOW	t _{W1}	10		ns
Width time for WR HIGH ⁽²⁾	t _{W2}	10		ns
Setup time, address valid before rising edge of WR	t _{SU1}	10		ns
Hold time, address valid after rising edge of WR	t _{H1}	5		ns
Setup time, data valid before rising edge of WR	t _{SU2}	10		ns
Hold time, data valid after rising edge of WR	t _{H2}	5		ns
Delay time from WR HIGH to CS HIGH	t _{D1}	10		ns

- (1) All input signals are specified with $t_R = t_F = 5$ ns ($10\frac{\%}{10}$ to 90% of BVDD) and timed from a voltage level of ($V_{IL} + V_{IH}$)/2.
- (2) One or more write cycles can be performed in one $\overline{\text{CS}}$ cycle.

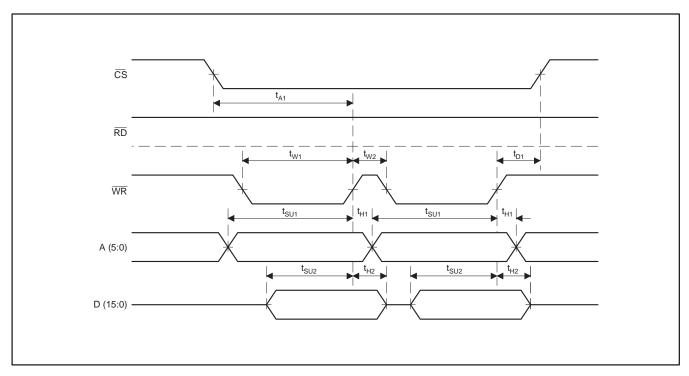


Figure 1-17. Mode 11 Write Access (Standard Mode)

3.4.4 Mode 11 Bus Access (TMS320c54xx DSP Family-Compatible Mode)

In the TMS320c54xx DSP family-compatible mode (M1 = 1 and M0 = 1), the host port uses $\overline{\text{CS}}$ (pin 57) together with $\overline{\text{WR}}$ (pin 57) as an R/W for independent read and write access to the ADS7869. Bit 0 of the PARALLEL register (address 27_H) must have a value of 0 to use this compatible mode.

In this mode, \overline{CS} , together with the R/ \overline{W} (which remains high), indicates to the ADS7869 that the host processor has requested a read data transfer (see Figure 1–18). The ADS7869 will output data to the host as long as the \overline{CS} is an active low.

To configure the registers, in the ADS7869 the host puts the R/\overline{W} signal to low to indicate that valid data is available on the bus. With the rising edge of the \overline{CS} , the data is latched into the ADS7869 (see Figure 1–19). The address for the ADS7869 must be valid before the \overline{CS} is set to low.

Before using this mode, the register bit 0 at address 27_H must be reset. The reset can be performed with a TMS320C54xx DSP write operation with the original mode 11, because the write access is similar to the write access of mode 11. (See *Mode 11 Bus Access [standard mode]* section.) This mode can perform read operations, after bit 0 is reset, as mentioned above.

3.4.4.1 Read Timing Characteristics(1)

Over recommended operating free-air temperature range at -40° C to $+85^{\circ}$ C, $AV_{DD} = 5$ V, $BV_{DD} = 3$ V - 5V.

PARAMETER	SYMBOL	MIN	MAX	UNIT
Delay time from CS LOW to output data not in tri-state mode	t _{D1}		8	ns
Access time from address valid to output data valid	t _{A1}		10	ns
Delay time from address not valid to output data not valid(2)	t _{D2}	0	8	ns
Delay time from CS HIGH to output data in tri-state mode	t _{D3}		8	ns

- (1) All input signals are specified with $t_R = t_F = 5$ ns $(10\frac{0}{M})$ to 90% of BVDD) and timed from a voltage level of $(V_{IL} + V_{IH})/2$.
- (2) One or more read cycles can be performed in one $\overline{\text{CS}}$ cycle.

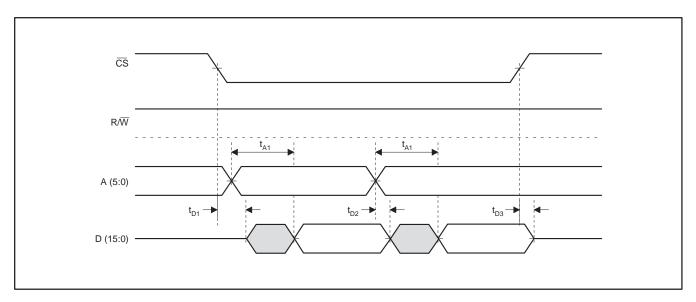


Figure 1–18. Mode 11 Read Access (TMS320c54xx mode)



SBAS253C - MAY 2003 - REVISED JANUARY 2005

3.4.4.2 Write Timing Characteristics⁽¹⁾

Over recommended operating free-air temperature range at -40° C to $+85^{\circ}$ C, $AV_{DD} = 5V$, $BV_{DD} = 3V - 5V$.

PARAMETER	SYMBOL	MIN	MAX	UNIT
Setup time from R/W LOW to CS LOW	t _{SU1}	0		ns
Hold time from CS HIGH to R/W HIGH	t _{H1}	5		ns
Setup time from address valid to CS LOW	t _{SU2}	10		ns
Hold time from CS HIGH to address not valid	t _{H2}	5		ns
Setup time from data valid to CS HIGH	t _{SU3}	10		ns
Hold time from CS HIGH to data not valid	t _{H3}	5		ns

(1) All input signals are specified with $t_R = t_F = 5$ ns (10% to 90% of BV_{DD}) and timed from a voltage level of ($V_{IL} + V_{IH}$)/2.

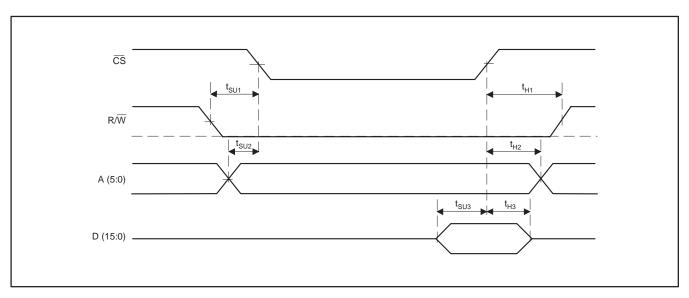


Figure 1–19. Mode 11 Write Access (TMS320c54xx mode)



3.5 Register Map

Table 1-10. Register Map Write 16-bit Data

	X X X X X X X X X X X X X X X X X X X	Chan Chan Chan Chan Chan Chan Chan Chan	nel IU, nel A1, nel A2, nel IV, nel B1, nel B2, nel IW, nel AN nel AN	write 1 , write 1 , write 2, write , write	O-bit of	fset DA ffset DA fset DA ffset DA ffset DA ffset DA offset D	C-value														
02H X X X X 03H X X X X 04H X X X X 05H X X X X 06H X X X X 07H X X X X 08H X X X X 09H X X X X 0AH X X X X 0BH X X X X 0DH X X X X X	x x x x x x x x x x x x x x x x x x x	Chan Chan Chan Chan Chan Chan Chan Chan	nel A1, nel A2, nel IV, nel B1, nel IW, nel AN nel AN nel AN	write 1 , write 1 , write 2, write , write	O-bit of O-b	ffset DA ffset DA ffset DA ffset DA ffset DA offset DA	AC-value AC-value AC-value AC-value AC-value														
03H X X X X 04H X X X X 05H X X X X 06H X X X X 07H X X X X 08H X X X X 09H X X X X 0AH X X X X 0BH X X X X 0DH X X X X X	X	Chan Chan Chan Chan Chan Chan Chan Chan	nel A2, nel IV, nel B1, nel B2, nel IW, nel AN nel AN	write 1 write 1 write 1 write 1 write 1 write 1 write 2, write 3, write	0-bit of 0-bit of 0-bit of 0-bit of 0-bit of 10-bit of 10-bit of 10-bit	ffset DA fset DA ffset DA ffset DA ffset DA offset D	AC-value C-value AC-value AC-value)))													
04 _H x x x x 05 _H x x x x 06 _H x x x x 07 _H x x x x 08 _H x x x x 09 _H x x x x 0A _H x x x x 0B _H x x x x 0C _H x x x x 0D _H x x x x	x x x x x x x x x x x x x x x x x x x	Chan Chan Chan Chan Chan Chan Chan Chan	nel IV, nel B1, nel B2, nel IW, nel AN nel AN nel AX	write 10 write 1 write 1 write 1 , write 1 , write 2, write 3, write	O-bit off O-bit of O-bit of O-bit of 10-bit	fset DA ffset DA ffset DA ffset DA offset I	C-value AC-value AC-value AC-value)													
05H X X X X 06H X X X X 07H X X X X 08H X X X X 09H X X X X 0AH X X X X 0BH X X X X 0CH X X X X 0DH X X X X	x x x x x x x x x x x x x x x x x x x	Chan Chan Chan Chan Chan Chan Chan Chan	nel B1, nel B2, nel IW, nel AN nel AN nel AN	write 1 write 1 write 1 , write 1, write 2, write 3, write	0-bit of 0-bit of 0-bit of 10-bit	ffset DA ffset DA ffset DA offset D	AC-value AC-value AC-value))													
06 _H x x x x 07 _H x x x x 08 _H x x x x 09 _H x x x x 0A _H x x x x 0B _H x x x x 0C _H x x x x C 0D _H x x x x C	x x x x x x x x x x x x x x x x x x Channel IU,	Chan Chan Chan Chan Chan Chan Chan Chan	nel B2, nel IW, nel AN nel AN nel AN	write 1 write 1 , write , write , write , write	0-bit of 0-bit of 10-bit 10-bit	ffset DA ffset DA offset [C-value))													
07H x x x x 08H x x x x 09H x x x x 0AH x x x x 0BH x x x x 0CH x x x x C 0DH x x x x C	x x x x x x x x x x x x x Channel IU,	Chan Chan Chan Chan Chan Chan Chan	nel IW, nel AN nel AN nel AN	write 1 1, write 2, write 3, write	0-bit of 10-bit 10-bit	fset DA offset [C-value)													
08H X X X X 09H X X X X 0AH X X X X 0BH X X X X 0CH X X X X 0DH X X X X	x x x x x x x x x x x x x x x x x x x	Chan Chan Chan Chan Chan	nel AN nel AN nel AN nel AX	1, write 2, write 3, write	10-bit 10-bit	offset [Channel B2, write 10-bit offset DAC-value										
09H X X X X 0AH X X X X 0BH X X X X 0CH X X X X 0DH X X X X C	x x x x x x x x x x x x x	Chan Chan Chan Chan	nel AN nel AN nel AX	2, write 3, write	10-bit		DAC-valu	10	Channel IW, write 10-bit offset DAC-value												
0A _H x x x x 0B _H x x x x 0C _H x x x x 0D _H x x x x C	x x x x x x Channel IU,	Chan Chan Chan	nel AN nel AX	3, write		~ ff ~ - + F	Channel AN1, write 10-bit offset DAC-value														
0BH x x x x 0CH x x x x 0DH x x x C	x x x x Channel IU,	Chan Chan	nel AX		10 hit	Channel AN2, write 10-bit offset DAC-value															
OCH X X X X ODH X X X X C	x x Channel IU,	Chan		Channel AN3, write 10-bit offset DAC-value Channel AX, write 10-bit offset DAC-value																	
OD _H x x x x C	Channel IU,																				
		write 10 L				ffset D/	AC-value	9													
	Channel A1,		-																		
	Channel A2,		_																		
	Channel IV, v																				
	Channel B1,		-																		
	Channel B2,		-																		
	Channel IW, write 12-bit gain DAC-value																				
	Channel AN1, write 12-bit gain DAC-value Channel AN2, write 12-bit gain DAC-value																				
			_																		
	Channel AN																				
	Channel AX,		_																		
	Channel BX,		_				N 10 20 10 20 20 20 20 20 20 20 20 20 20 20 20 20	D	A O I												
19 _H	X X	X	Х				3-bit win		INPU												
1A _H x x x x	X X	X	X	X	Х	Х		X													
1B _H x x x x x	х х	Х	Х	Х	Х	Х	Х	<u> </u>	vvrite 4	-DIT COU	inter control										
1C _H Unwriteable (don't care) 1D _H	Counter 1	L write 46	Shitvo	luo in F	DGEC	OLINIT	COLUMBO	r													
1E _H	Counter			ole (dor			counte	1													
1F _H				ole (dor																	
20 _H				ole (dor																	
21 _H	Counter 2			•			Counte	r													
22 _H	OGUITIEI 2			ole (dor			- counte	'													
23 _H				ole (dor																	
24 _H	WI	rite 16-bit		`	′		er														
25 _H		te 16-bit																			
26 _H Counter interrupt enables	х х	X	x	X	_1LO	x	Х	Х	Х	FIFO	interrupt enables										
27 _H	x x	X	X	X	X	X	X	X	X	X	PARALLEL										
28 _H		write 16-								.,											
29 _H –3F _H				ole (don																	

NOTE: 'x' means unwriteable (don't care)

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SBAS253C - MAY 2003 - REVISED JANUARY 2005

Table 1-11. Register Map Read 16-bit Data

ADDRESS	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
00 _H	FIFO c	lata		1	1	1			1	1	1	1	1	1	1	L
01 _H	Chann	el IU, re	ad 10-b	it offset	DAC-va	alue (1)										
02 _H	Chann	el A1, re	ead 10-b	oit offset	DAC-v	alue (1)										
03 _H	Chann	el A2, re	ead 10-b	oit offset	DAC-v	alue (1)										
04 _H	Chann	el IV, rea	ad 10-b	it offset [DAC-va	lue (1)										
05 _H	Chann	el B1, re	ead 10-b	oit offset	DAC-v	alue (1)										
06 _H	Chann	el B2, re	ead 10-b	oit offset	DAC-v	alue (1)										
07 _H	Chann	el IW, re	ead 10-b	it offset	DAC-va	alue (1)										
08 _H	Chann	el AN1,	read 10	-bit offse	t DAC-	value (1)									
09 _H	Chann	el AN2,	read 10	-bit offse	t DAC-	value (1)									
0A _H	Chann	el AN3,	read 10	-bit offse	t DAC-	value (1)									
0B _H	Chann	el AX, re	ead 10-	bit offset	DAC-	value (1))									
0C _H	Chann	el BX, re	ead 10-l	oit offset	DAC-v	alue (1)										
0D _H	0	0	0	0	Chan	nel IU, re	ead 12	-bit gai	n DAC	-value						
0E _H	0	0	0	0	Chan	nel A1, r	ead 12	-bit ga	in DA0	C-value	;					
0F _H	0	0	0	0	Chan	nel A2, r	ead 12	-bit ga	in DA0	C-value	;					
10 _H	0	0	0	0	Chan	nel IV, re	ad 12-	bit gai	n DAC	-value						
11 _H	0	0	0	0	Chan	nel B1, r	ead 12	-bit ga	in DA0	C-value)					
12 _H	0	1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1														
13 _H	0															
14 _H	0	0 0 0 Channel AN1, read 12-bit gain DAC-value														
15 _H	0	0	0	0		nel AN2,										
16 _H	0	0	0	0		nel AN3,										
17 _H	0	0	0	0		nel AX, r										
18 _H	0	0	0	0	l	nel BX, r		_								
19 _H	(3)	(3)	(3)	(3)	(3)	(3)	(3)	(3)					window D			
1A _H	0	0	0	0	0	0	0	0	0	0	0	DAV	0	INPU	JT	
1B _H				and statu												
1C _H						GCNT1	-									
1D _H						GCNT1										
1E _H						GPRD1										
1F _H						GTIME1										
20 _H						GCNT2										
21 _H						GCNT2										
22 _H						GPRD2										
23 _H						GTIME2	registe	er								
24 _H				IFO_TE		ster	T = -	1 = -	1	1	1	1,	T 17:0	1	1	Line
25 _H (2)				registe	r		B2	B1	A2	A1	UC	VC	WC	UI	VI	WI
26 _H		NTERR				1.	T -	T -	Ι	1.		T .	T.a.	1.	1.	Latatite
27 _H	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	PARALLEL
28 _H	Read (
29 _H –3F _H	Unuse	d (read	0000H)													

⁽¹⁾ MSB is copied to upper bits to achieve 16-bit two's complement values.

⁽²⁾ The lower 10 bits are the comparator outputs.

⁽³⁾ The MSB of the 8-bit DAC is copied in the upper 8 bits.



3.6 Register Descriptions

The following table shows the symbols that are used in this section. The last number in the symbol represents the reset value.

R	Readable Bit
W	Writeable Bit
U	Unused
0/1	Value After Reset

The clock has to be running when the registers in the register map are accessed.

3.6.1 FIFO Data Register (00_H)

The FIFO Data Register is at address 00_H in the register map. The output word of the FIFO is in16-bit format. The resolution of the ADCs is 12 bits. Output data from each of the ADCs is in binary two's complement format. The four MSBs are used for channel identification. The format of the output word is shown in Table 1–12.

There are three words stored in the FIFO for each conversion. There must be three read accesses to this register to get all three conversion values out of the FIFO.

Table 1–12. FIFO Output Word Format

R0	R0	R0	R0	R0	R0	R0	R0	R0	R0	R0	R0	R0	R0	R0	R0
CA3	CA2	CA1	CA0	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
bit 15	bit 14	bit 13	bit 12	bit 11	bit 10	bit 9	bit 8	bit 7	bit 6	bit 5	bit 4	bit 3	bit 2	bit 1	bit 0

	CA3-0: INPUT CHANNEL ADDRESS BITS	
Bit 15–12:	0000 = Data from IU input	
	0001 = Data from A1 input	
	0010 = Data from A2 input	
	0011 = Data from IV input	
	0100 = Data from B1 input	
	0101 = Data from B2 input	
	0110 = Data from IW input	
	0111 = Data from AN1 input	
	1000 = Data from AN2 input	
	1001 = Data from AN3 input	
	1010 = Data from AX input	
	1011 = Data from BX input	
	1100 = Unused	
	1101 = Unused	
	1110 = Unused	
	1111 = Unused	
Bit 11-0:	DATA11-0: The output from the ADCs	

In test mode, the upper four bits are copied from Bit 11 of the written data; see the FIFO Test Register (24_H) section.



SBAS253C - MAY 2003 - REVISED JANUARY 2005

3.6.2 Offset Registers (01_H to $0C_H$)

The Offset Registers are stored at the addresses $01_{\rm H}$ to $0C_{\rm H}$. The Offset Registers are 10 bits wide and represented in the two's complement format. The sign bit is copied in bit locations 15 to 10. This copy is only performed by a read access (that is, bits 15 to 10 must not be correctly set, in order to achieve the copy of the sign bit). The data format is shown in Table 1–13. The valid offset adjustment values are from –511 (201_H) to +511 (1FF_H). The value –512 (200_H) is not allowed.

Table 1-13. Offset Registers

R0	R0	R0	R0	R0	R0	RW0									
D9	D9	D9	D9	D9	D9	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
bit 15	bit 14	bit 13	bit 12	bit 11	bit 10	bit 9	bit 8	bit 7	bit 6	bit 5	bit 4	bit 3	bit 2	bit 1	bit 0

Bit 15–9:	D9: The MSB of the offset
Bit 8-0:	D9–0: The 10 bits of the offset value

3.6.3 Gain Registers ($0D_H$ to 18_H)

The Gain Registers are stored at the addresses 0D_H to 18_H. The Gain Registers are 12 bits wide. The gain value is stored in a straight binary format. The data format is shown in Table 1–14.

Table 1-14. Gain Registers

R0	R0	R0	R0	RW0	RW0	RW0	RW0	RW0	RW0	RW0	RW0	RW0	RW0	RW0	RW0
0	0	0	0	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
bit 15	bit 14	bit 13	bit 12	bit 11	bit 10	bit 9	bit 8	bit 7	bit 6	bit 5	bit 4	bit 3	bit 2	bit 1	bit 0

Bit 15–12:	Always read as '0'; don't care at write
Bit 11-0:	D11–0: The 12 bits of the gain value

3.6.4 WINDAC Register (19_H)

The WINDAC Register is located in address 19_H . The WINDAC Register sets the output of the 8-bit DAC used by the window comparators. The word is in 8-bit straight binary format. The output voltage is a function of the register value and the internal reference voltage. (See Table 1–3.) The format of the data word is shown in Table 1–15.

Table 1–15. WINDAC Register

R0	R0	R0	R0	R0	R0	R0	R0	RW0							
D7	D7	D7	D7	D7	D7	D7	D7	D7	D6	D5	D4	D3	D2	D1	D0
bit 15	bit 14	bit 13	bit 12	bit 11	bit 10	bit 9	bit 8	bit 7	bit 6	bit 5	bit 4	bit 3	bit 2	bit 1	bit 0

Bit 15–8:	D7: MSB from DAC input data
Bit 7–0:	D7–0: The 8 bits input to Digital-to-Analog Converter



SBAS253C - MAY 2003 - REVISED JANUARY 2005

3.6.5 Control Register (1A_H)

The Control Register is located in address 1A_H. The control register contains the input selection and the DAV pin control. (See the *FIFO* section for additional information.) The format of the Control Register is shown in Table 1–16. For more about the input selection, see the *Vecana Interface* section.

Table 1-16. Control Registers

R0	R0	R0	R0	R0	R0	R0	R0	R0	R0	R0	RW0	R0	RW0	RW0	RW0
0	0	0	0	0	0	0	0	0	0	0	DAV	0	12	l1	10
bit 15	bit 14	bit 13	bit 12	bit 11	bit 10	bit 9	bit 8	bit 7	bit 6	bit 5	bit 4	bit 3	bit 2	bit 1	bit 0

Bit 15-5, 3:	Unused (read as '0'); don't care at write
Bit 4:	DAV: The 8 bits input to Digital-to-Analog Converter 1 = DAV signal active HIGH 0 = DAV signal active LOW
Bit 2-0:	I2–0: Input channel selection bits 000 = AN3 for ADC ₃ 001 = AX for ADC ₁ , BX for ADC ₂ , and AN3 for ADC3 010 = A2 via SH ₁ for ADC ₁ , B2 via SH ₃ for ADC ₂ and AN2 for ADC ₃ 011 = A2 via SH ₂ for ADC ₁ , B2 via SH ₄ for ADC ₂ and AN2 for ADC ₃ 100, 101, 110 = A1 for ADC ₁ , B1 for ADC ₂ and AN1 for ADC ₃ 111 = IU for ADC ₁ , IV for ADC ₂ and IW for ADC ₃



SBAS253C - MAY 2003 - REVISED JANUARY 2005

3.6.6 Counter Control/Status Register (1B_H)

The Counter Control/Status Register is located in address 1_{BH}. The counter control/status register CCTRLSTAT is a combined control register for the filtered input of the counters and a status register for the over- or under-flow status of the counters and the filtered input signals strobed by HOLD1. See the *Digital Counters* section for more information on this topic.

When the filter bits FxxE are set, the appropriate input is synchronized with the system clock and a digital filter processes the input signal. If the bit is reset, the signals are just synchronized.

The overflow states EOx/TOx are set when the appropriate counter has reached the value FFFF_H. This indicates when the time, between two edges of the input signals, is greater than 4ms at 16MHz. Only the time counter keeps its value until a counter reset is performed. See the *Reset Register* section for additional information.

The filtered values of the counter inputs CNTA2, CNTA1, CNTB2 and CNTB1 are sampled with the synchronous signal HOLD1 and are stored in the appropriate bits FB1, FA1, FB2 and FA2. The format of the Counter Control/Status Register is described in Table 1–17.

Table 1-17. Counter Control/Status Register

R0	R0	R0	R0	R0	R0	R0	R0	R0	R0	R0	R0	RW1	RW1	RW1	RW1
FA1	FB1	FA2	FB2	0	0	0	0	EO2	TO2	EO1	TO1	FA2E	FB2E	FA1E	FB1E
bit 15	bit 14	bit 13	bit 12	bit 11	bit 10	bit 9	bit 8	bit 7	bit 6	bit 5	bit 4	bit 3	bit 2	bit 1	bit 0

Bit 15:	FA1: Synchronously strobed and filtered CNTA1 signal
Bit 14:	FB1: Synchronously strobed and filtered CNTB1 signal
Bit 13:	FA2: Synchronously strobed and filtered CNTA2 signal
Bit 12:	FB2: Synchronously strobed and filtered CNTB2 signal
Bit 7:	EO2 : EDGECNT2, over- or under-flow state 1 = when EDGECNT1 reached FFFF _H 0 = when EDGECNT1 is other than FFFF _H
Bit 6:	TO2: TIMECOUNT2, over- or under-flow state 1 = when TIMECOUNT1 reached FFFFH 0 = when TIMECOUNT1 is other than FFFFH
Bit 5:	EO1 : EDGECNT1, over- or under-flow state 1 = when EDGECNT0 reached FFFF _H 0 = when EDGECNT0 is other than FFFF _H
Bit 4:	TO1: TIMECOUNT1, over- or under-flow state 1 = when TIMECOUNT0 reached FFFFH 0 = when TIMECOUNT0 is other than FFFFH
Bit 3:	FA2E: Enable of digital filter input CNTA2 1 = Input signal of CNTA2 will be filtered 0 = Input signal of CNTA2 will not be filtered
Bit 2:	FB2E: Enable of digital filter input CNTB2 1 = Input signal of CNTB2 will be filtered 0 = Input signal of CNTB2 will not be filtered
Bit 1:	FA1E: Enable of digital filter input CNTA1 1 = Input signal of CNTA1 will be filtered 0 = Input signal of CNTA1 will not be filtered
Bit 0:	FB1E: Enable of digital filter input CNTB1 1 = Input signal of CNTB1 will be filtered 0 = Input signal of CNTB1 will not be filtered

SBAS253C - MAY 2003 - REVISED JANUARY 2005

3.6.7 Edge Count Register (1 C_H , 1 D_H , 2 O_H and 21 $_H$)

There are four shadow registers for the two edge counters. The registers SYEDGCNT1 and SYEDGCNT2, synchronous edge count 1 (in address $1D_H$), and synchronous edge count 2 (in address 21_H), latch the values, from the edge counters, when the synchronous hold signal $\overline{HOLD1}$ is set to low.

Registers ASEDGCNT1, ASEDGCNT2, asynchronous edge count 1 (in address $1C_H$), and asynchronous edge count 2 (in address 20_H), latch the values from the edge counters when the asynchronous hold signal $\overline{HOLD2}$ is set to low.

An initial value is given to the edge counter 1, EDGECNT1, by writing into the register SYEDGCNT1. An initial value is given to the edge counter 2, EDGECNT2, by writing into the register SYEDGCNT2; see Table 1–18.

Table 1-18. Synchronous Latched Edge Count Register

RW0	RW0	RW0	RW0	RW0	RW0	RW0	RW0	RW0	RW0	RW0	RW0	RW0	RW0	R-	R-
D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
bit 15	bit 14	bit 13	bit 12	bit 11	bit 10	bit 9	bit 8	bit 7	bit 6	bit 5	bit 4	bit 3	bit 2	bit 1	bit 0

Bit 15–2:	D15-2: The 14 MSBs of the synchronous latched edge counters
	D1–0 : The 2 LSBs of the synchronous latched edge counters. The value is adjusted to the value of the CNTAx and CNTBx by a write access to these registers or a reset condition.

CNTAx	CNTBx	EDGECNTx bit 1	EDGECNTx bit 0	Position of the Angle
0	0	0	0	1st Quadrant
1	0	0	1	2nd Quadrant
1	1	1	0	3rd Quadrant
0	1	1	1	4th Quadrant

The data can only be read from the asynchronous latched registers ASEDGCNT1 and ASEDGCNT2; see Table 1–19.

Table 1-19. Asynchronous Latched Edge Count Register

	R0	R0	R0	R0	R0	R0	R0	R0	R0	R0	R0	R0	R0	R0	R0	R0
Г	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
Γ	bit 15	bit 14	bit 13	bit 12	bit 11	bit 10	bit 9	bit 8	bit 7	bit 6	bit 5	bit 4	bit 3	bit 2	bit 1	bit 0

Bit 15–0: D15–0: The 16 bits of the asynchronous latched edge counters

3.6.8 Edge Period Register (1 E_H and 2 2_H)

There are two read-only shadow registers for the two edge-period registers. The registers SYEDGPRD1 and SYEDGPRD2, synchronous edge period 1 (in address $1E_H$) and synchronous edge period 2 (in address 22_H), latch the values from the edge period registers when the synchronous hold signal $\overline{HOLD1}$ is set to low. The Edge Period Register is described in Table 1–20.

Table 1-20. Edge Period Register

R0	R0	R0	R0	R0	R0	R0	R0	R0	R0	R0	R0	R0	R0	R0	R0
D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
bit 15	bit 14	bit 13	bit 12	bit 11	bit 10	bit 9	bit 8	bit 7	bit 6	bit 5	bit 4	bit 3	bit 2	bit 1	bit 0

Bit 15-0:	D15-0: The 16 bits of the synchronous latched edge period registers	



SBAS253C - MAY 2003 - REVISED JANUARY 2005

3.6.9 Edge Time Period Register (1 F_H and 2 3_H)

There are two read-only shadow registers for the two edge time counters. The registers SYEDGTIME1 and SYEDGTIME2, synchronous edge time 1 (in address $1F_H$) and synchronous edge time 2 (in address 23_H), latch the values from the edge time counters when the synchronous hold signal $\overline{HOLD1}$ is set to low. The Edge Time Register is described in Table 1–21.

Table 1-21. Edge Time Period Register

R0	R0	R0	R0	R0	R0	R0	R0	R0	R0	R0	R0	R0	R0	R0	R0
D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
bit 15	bit 14	bit 13	bit 12	bit 11	bit 10	bit 9	bit 8	bit 7	bit 6	bit 5	bit 4	bit 3	bit 2	bit 1	bit 0

Bit 15–0:	D15-0: The 16 bits of the synchronous latched edge time counters
	,

3.6.10 FIFO Test Register (24_H)

The purpose of the FIFO Test Register, in address $24_{\rm H}$, is to test the FIFO during production test; the FIFO is filled with a defined pattern via this register. The internal FIFO structure can be verified by reading the patterns of the FIFO data register. When the FIFO test is enabled, the multiplexers are switched and lead the data (of the FIFO test register) into the FIFO, instead of the normal ADC data; to simulate the three ADCs, the data is latched into the FIFO three times. To distinguish between the channels, the first data is unchanged to simulate ADC₁, the second data is inverted to simulate ADC₂, and the six LSBs of the third data are inverted to simulate ADC₃. While the FIFO test is enabled, a total of three data words will be stored in the FIFO, with one write instruction. In order to fill the entire FIFO register with test data, 10 writes must be performed. The test data is written into the FIFO only when the four enable bits have the value $A_{\rm H}$. **This register should not be used in normal operation.** The format of the output word is shown in Table 1–22.

Table 1-22. FIFO Test Register

RW0	RW0	RW0	RW0	RW0	RW0	RW0	RW0	RW0	RW0	RW0	RW0	RW0	RW0	RW0	RW0
E3	E2	E1	E0	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
bit 15	bit 14	bit 13	bit 12	bit 11	bit 10	bit 9	bit 8	bit 7	bit 6	bit 5	bit 4	bit 3	bit 2	bit 1	bit 0

Bit 15–12:	E3-0: Input channel address bits
	0000 = Disable FIFO test
	1001 = Disable FIFO test
	1010 = Enable FIFO test write procedure
	1011 = Disable FIFO test
	1111 = Disable FIFO test
Bit 11-0:	DATA11-0: The input data that will be written into the FIFO registers

In FIFO test mode the four channel bits are copied from Bit 11 of the written data.

3.6.11 Comparator Test Register (25_H)

The purpose of the Comparator Test Register, in address 25_H , is to apply a defined pattern to the comparator output pins. This feature is for testing algorithms in the DSP or testing the hardware controlled by the comparator outputs. To enable the comparator test, the enable part of the register must contain the value $0C_H$. **This register should not be used in normal operation.** By reading the Comparator Test register, the comparator outputs are sent back in order to allow the host to read the actual comparator outputs in one cycle. The format of the output word is shown in Table 1–23.

Table 1-23. Comparator Test Register

Γ	RW0	RW0	RW0	RW0	RW0	RW0	RW-									
Γ	E5	E4	E3	E2	E1	E0	A1/B2	B1	A2	B2/A1	UC	VC	WC	UI	VI	WI
Γ	bit 15	bit 14	bit 13	bit 12	bit 11	bit 10	bit 9	bit 8	bit 7	bit 6	bit 5	bit 4	bit 3	bit 2	bit 1	bit 0

Bit 15–10:	E5–0: Input channel address bits
	000000 = Disable COMPARATOR TEST
	001011 = Disable COMPARATOR_TEST
	001100 = Enable COMPARATOR_TEST write procedure
	001101 = Disable COMPARATOR_TEST
	111111 = Disable COMPARATOR_TEST
Bit 9:	A1: Control bit of position sensor, sign comparator A1 output
	1 = Comparator output A1, set HIGH
	0 = Comparator output A1, set LOW By reading this bit, comparator output B2 is read
Bit 8:	B1: Control bit of position sensor, sign comparator B1 output
DIL O.	1 = Comparator output B1, set HIGH
	0 = Comparator output B1, set LOW
Bit 7:	A2: Control bit of position sensor, sign comparator A2 output
	1 = Comparator output A2, set HIGH
	0 = Comparator output A2, set LOW
Bit 6:	B2: Control bit of position sensor, sign comparator B2 output
	1 = Comparator output B2, set HIGH 0 = Comparator output B2, set LOW
	By reading this bit, comparator output A1 is read
Bit 5:	UC: Control bit phase U current sign comparator
	1 = Comparator output U_COMP, set HIGH
	0 = Comparator output U_COMP, set LOW
Bit 4:	VC: Control bit phase V current sign comparator 1 = Comparator output V_COMP, set HIGH
	0 = Comparator output V_COMP, set HIGH
Bit 3:	WC: Control bit phase W current sign comparator
Dit o.	1 = Comparator output W_COMP, set HIGH
	0 = Comparator output W_COMP, set HIGH
Bit 2:	UI: Control bit phase U current window comparator
	1 = Comparator output U_ILIM, set HIGH
	0 = Comparator output U_ILIM, set LOW
Bit 1:	VI: Control bit phase V current window comparator
	1 = Comparator output V_ILIM, set HIGH 0 = Comparator output V_ILIM, set LOW
Bit 0:	WI: Control bit phase W current window comparator
Dit V.	1 = Comparator output W_ILIM, set HIGH
	0 = Comparator output W_ILIM, set LOW



SBAS253C - MAY 2003 - REVISED JANUARY 2005

3.6.12 Interrupt Register (26_H)

The Interrupt Register, in address 26_H, contains the interrupt source and interrupt control bits. The bits xOxF are set when a particular counter had an over- or under-flow. The bits remain set until the Interrupt Register is read; this is independent of whether the counter over- or under-flow states remain or not. The counter over- or under-flow interrupt is enabled when the appropriate xOxE bits are set.

The FFF bit, FIFO full flag, will be set when the FIFO is (or was) full and remains set until the Interrupt Register is read, independent of whether the FIFO is full or not. The FF bit, FIFO full, indicates whether the FIFO is full or not. The FFF bit is cleared when the Interrupt Register is read. The FIFO full interrupt is enabled when the bit FFE (or FIFO full enable) is set.

The FEF bit, FIFO empty flag, will be set when the FIFO is (or was) empty and remains set until the Interrupt Register is read, independent of whether the FIFO is empty or not. The FE bit, FIFO empty, indicates if the FIFO is empty or not. The bit FEF is cleared when the Interrupt Register is read. The FIFO empty interrupt is enabled when the FEE bit, FIFO empty enable, is set. For more information about the Interrupt pin, see the *Interrupt* section. Table 1–24 describes the Interrupt Register.

Table 1–24. Interrupt Register

RW0	RW0	RW0	RW0	R0	R0	R0	R0	R0	R0	R0	R0	R0	R0	RW0	RW0
EO2E	TO2E	EO1E	TO1E	EO2F	TO2F	EO1F	TO1F	0	0	FF	FE	FFF	FEF	FFE	FEE
bit 15	bit 14	bit 13	bit 12	bit 11	bit 10	bit 9	bit 8	bit 7	bit 6	bit 5	bit 4	bit 3	bit 2	bit 1	bit 0

Bit 15:	EO2E : Edge counter 2, EDGECNT2, over- or under-flow interrupt enable bit 1 = Interrupt enable 0 = Interrupt disable	
Bit 14:	TO2E : Time counter 2, TIMECOUNT2, over- or under-flow interrupt enable bit 1 = Interrupt enable 0 = Interrupt disable	
Bit 13:	EO1E : Edge counter 1, EDGECNT1, over- or under-flow interrupt enable bit 1 = Interrupt enable 0 = Interrupt disable	
Bit 12:	TO1E: Time counter 1, TIMECOUNT1, over- or under-flow interrupt enable bit 1 = Interrupt enable 0 = Interrupt disable	
Bit 11:	EO2F: Edge counter 2, EDGECNT2, over- or under-flow flag 1 = EDGECNT2 over- or under-flow occurred 0 = EDGECNT2 over- or under-flow did not occur	
Bit 10:	TO2F: Time counter 2, TIMECOUNT2, over- or under-flow flag 1 = TIMECOUNT2 over- or under-flow occurred 0 = TIMECOUNT2 over- or under-flow did not occur	
Bit 9:	EO1F: Edge counter 1, EDGECNT1, over- or under-flow flag 1 = EDGECNT1 over- or under-flow occurred 0 = EDGECNT1 over- or under-flow did not occur	
Bit 8:	TO1F: Time counter 1, TIMECOUNT1, over- or under-flow flag 1 = TIMECOUNT1 over- or under-flow occurred 0 = TIMECOUNT1 over- or under-flow did not occur	
Bit 7–6:	Unused (read as '0')	



SBAS253C - MAY 2003 - REVISED JANUARY 2005

Interrupt Register, continued

Bit 5:	FF: FIFO full state 1 = FIFO is full 0 = FIFO is not full
Bit 4:	FE: FIFO empty state 1 = FIFO is empty 0 = FIFO is not empty
Bit 3:	FFF: FIFO full flag 1 = FIFO is or was full 0 = FIFO is not or was not full
Bit 2:	FEF: FIFO empty flag 1 = FIFO is or was empty 0 = FIFO is not or was not empty
Bit 1	FFE: FIFO full interrupt enable bit 1 = Interrupt enable 0 = Interrupt disable
Bit 0:	FEE: FIFO empty interrupt enable bit 1 = Interrupt enable 0 = Interrupt disable

3.6.13 Parallel Register (27_H)

The Parallel Register, in address 27_H, controls the parallel interface mode 11; see the *Mode 11 Bus Access* sections. The Parallel Register has no effect on modes 00, 01, and 10. There is only one bit present in the Parallel Register, the M bit. The format of the Parallel Register is shown in Table 1–25.

Table 1-25. Parallel Register

١	R0	R0	R0	R0	R0	R0	R0	R0	R0	R0	R0	R0	R0	R0	R0	RW1
١	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	М
	bit 15	bit 14	bit 13	bit 12	bit 11	bit 10	bit 9	bit 8	bit 7	bit 6	bit 5	bit 4	bit 3	bit 2	bit 1	bit 0

Bit 15–1:	Unused (read as '0')
Bit 0:	M: Set up the type of the parallel interface
	1 = Parallel interface, mode 11 (default)
	0 = TMS320c54xx DSP family-compatible parallel interface



SBAS253C - MAY 2003 - REVISED JANUARY 2005

3.6.14 Reset Register (28_H)

The Reset Register, in address 28_H , can either reset the ADS7869 entirely, or simply reset the counters. Writing an AA_H pattern to the C_X bits will reset both counter 1 and counter 2, and all registers related to the counters. Writing an AA_H pattern to the S_X bits forces the ADS7869 into a reset state; both the digital and the analog sections are reset. The Reset Register is a write-only register. If the Reset Register is read, the data 0000_H will be received. The format of the input word is shown in Table 1–26. To reset the complete ADS7869, the pattern $AAAA_H$ should be written to the Reset Register.

Once the Reset Register activates a system reset, the register must not be rewritten to in order to deactivate the reset condition. Writing another pattern to the C_X bits (other than AA_H) deactivates a reset condition of the counters or a reset condition of the device.

For more information about reset conditions, see the *Reset* section.

Table 1-26. Reset Register

	W0	W0	W0	W0	W0	W0	W0	W0	W0	W0	W0	W0	W0	W0	W0	W0
Г	S7	S6	S5	S4	S3	S2	S1	S0	C7	C6	C5	C4	C3	C2	C1	C0
Г	bit 15	bit 14	bit 13	bit 12	bit 11	bit 10	bit 9	bit 8	bit 7	bit 6	bit 5	bit 4	bit 3	bit 2	bit 1	bit 0

Bit 15–8:	S7–0: Reset control of entire ADS7869 (both digital and analog sections)							
	00000000 = No effect on ADS7869							
	10101001 = No effect on ADS7869							
	10101010 = Reset entire ADS7869							
	10101011 = No effect on ADS7869							
	11111111 = No effect on ADS7869							
Bit 7-0:	C7-0: Reset control of both counters and related registers of ADS7869							
	00000000 = No effect on ADS7869							
	10101001 = No effect on ADS7869							
	10101010 = Reset both counters in ADS7869							
	10101011 = No effect on ADS7869							
	11111111 = No effect on ADS7869							



3.7 FIFO

The FIFO of the ADS7869 is organized as a 32-word ring buffer with 16 bits per word, shown in Figure 1–20.

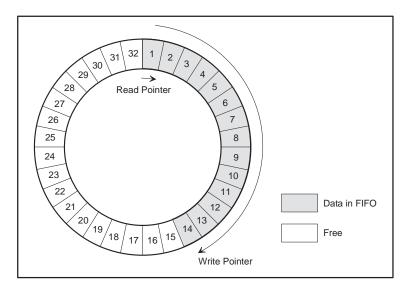


Figure 1-20. FIFO Structure

The converted data of the ADS7869 is automatically written into the FIFO. To control the writing and reading process, a write pointer and a read pointer are used. The read pointer always shows the location that contains the last read data. The write pointer indicates the location that contains the last written sample. The converted values are written in a predefined sequence to the circular buffer, beginning with ADC $_1$ and ending with ADC $_3$. The channel number is stored with the ADC data. The data of the FIFO is read through the FIFO register at address 00_H ; its format is presented in Table 1–27. The table shows that the channel information for the converted channel data, is continually maintained. The address 00_H in the register map shows only the data to which the read pointer is directed.

The FIFO generates the DAV signal; see Figure 1–22 on page 51. In VECANA mode, this signal is low; it indicates that the ADS7869 is converting data (see Figure 1–10 on page 26). In the other modes, the DAV indicates that data in the FIFO is available. The DAV signal can be configured as either a positive or negative signal; see the *Control Register* section.

Table 1–27. FIFO 16-bit Data Read Format																
ADDRESS	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
00 _H	0	0	0	0	ADC ₁	NDC ₁ value, channel IU, included offset and gain compensation										
00 _H	0	0	0	1	ADC ₁	value, d	channe	l A1, i	nclude	d offse	t and g	ain cor	npensatio	n		
00 _H	0	0	1	0	ADC ₁	value, d	channe	l A2, i	nclude	d offse	t and g	ain cor	npensatio	n		
00 _H	0	0	1	1	ADC ₂	DC ₂ value, channel IV, included offset and gain compensation										
00 _H	0	1	0	0	ADC ₂	value, d	channe	l B1, i	nclude	d offse	t and g	ain cor	npensatio	n		
00 _H	0	1	0	1	ADC ₂	value, d	channe	l B2, i	nclude	d offse	t and g	ain cor	npensatio	n		
00 _H	0	1	1	0	ADC ₃	value, d	channe	l IW, i	nclude	d offset	and ga	ain cor	npensatio	n		
00 _H	0	1	1	1	ADC ₃	value, d	channe	I AN1	, includ	ed offs	et and	gain c	ompensat	ion		
00 _H	1	0	0	0	ADC ₃	value, d	channe	I AN2	, includ	ed offs	et and	gain c	ompensat	ion		
00 _H	1	0	0	1	ADC ₃	value, d	channe	I AN3	, includ	ed offs	et and	gain c	ompensat	ion		
00 _H	1	0	1	0	ADC ₁	value, d	channe	l AX, i	nclude	d offse	t and g	ain cor	mpensatio	n		
00 _H	1	0	1	1	ADC ₂	value, d	channe	l BX, i	nclude	d offse	t and g	ain cor	mpensatio	n		
00 _H	1	1	0	0	Not exi	isting										
00 _H	1	1	0	1	Not exi	isting										
00 _H	1	1	1	0	Not exi	isting										
00 _H	1	1	1	1	Not exi	isting										

Table 1-27. FIFO 16-bit Data Read Format



SBAS253C - MAY 2003 - REVISED JANUARY 2005

The DAV signal becomes active when the write pointer is ahead of the read pointer. The DAV signal becomes inactive again when the read pointer equals the write pointer (that is, when the FIFO is empty).

When the ADCs are writing data into the FIFO, and the write pointer is more than 32 steps ahead of the read pointer, a FF (FIFO Full) state will be set. FF is cleared when the first FIFO read operation is performed. To synchronize the pointers after an FF state, the FIFO should be read out until a FE (FIFO Empty) occurs.

If a read is attempted, while the read and write pointers are equal, the read pointer will not increase; the same data (the data with the same channel number) is read again. When this occurs, an FE state is set. The FE state is cleared when new data is written into the FIFO. The read pointer will not go beyond the write pointer. Both FF and FE go into the Interrupt section. The functional block diagram of the FIFO is shown in Figure 1–21.

The purpose of the test data is to verify the FIFO structure for the development of an application. This is described in the *FIFO Test Register* section. **This register should not be used in normal operation.**

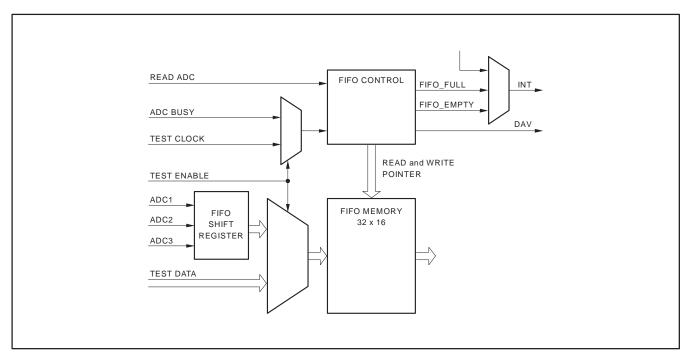


Figure 1–21. FIFO Block Diagram



ADS7869



DAV Timing Characteristics(1) 3.7.1

Over recommended operating free-air temperature range at -40° C to $+85^{\circ}$ C, $AV_{DD} = 5V$, $BV_{DD} = 3V - 5V$.

PARAMETER	SYMBOL	MIN	MAX	UNIT
Delay time from 14th rising CLK to falling DAV(2)	t _{D1}		50	ns
Setup time from RD HIGH to next rising CLK	t _{SU1}	8		ns
Delay time from rising CLK to rising DAV(2)(3)	t _{D2}		50	ns
Setup time from CS HIGH to next rising CLK	t _{SU2}	8		ns
Delay time from rising CLK to rising DAV(2)(3)	t _{D3}		50	ns
Setup time from SPISTE HIGH to next rising CLK	t _{SU3}	8		ns
Delay time from rising CLK to rising DAV(2)(3)	t _{D4}		50	ns

- (1) All input signals are specified with t_R = t_F = 5ns (10% to 90% of BV_{DD}) and timed from a voltage level of (V_{II} + V_{IH})/2.
- (2) With the DAV bit in the Control register (14H), the DAV signal can have opposite polarity.
- (3) Only applicable when the last data is read from the FIFO

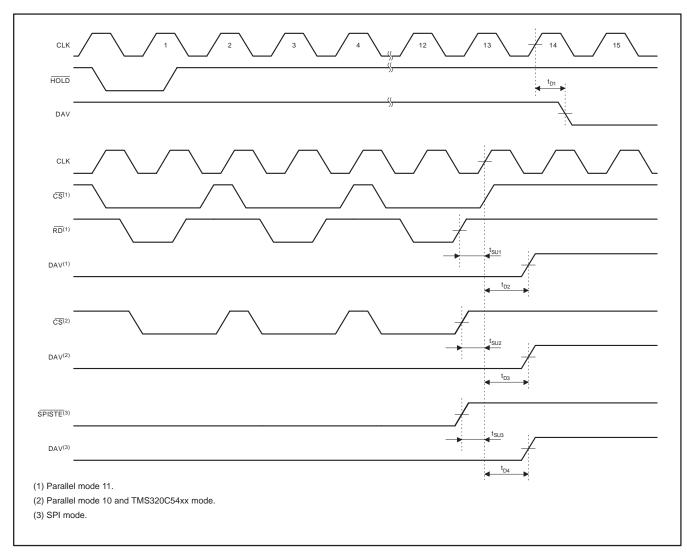


Figure 1-22. Timing of the DAV Signal

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SBAS253C - MAY 2003 - REVISED JANUARY 2005

3.8 Digital Counter Modules

The interface of the ADS7869 for the analog position sensors has the following features:

- Up to 16MHz operation frequency
- Error-safe state machine for fully four-quadrant decoding
- High noise immunity:
 - Differential signal inputs
 - Analog input comparators with hysteresis
 - Schmitt trigger digital inputs
- Digital Noise Filter
- 16-bit binary Up/Down counters with over- and under-flow detection
- Synchronous to the system clock
- Asynchronous and synchronous latching of the counter values at the same time as the ADC values are sampled and held
- Five shadow registers

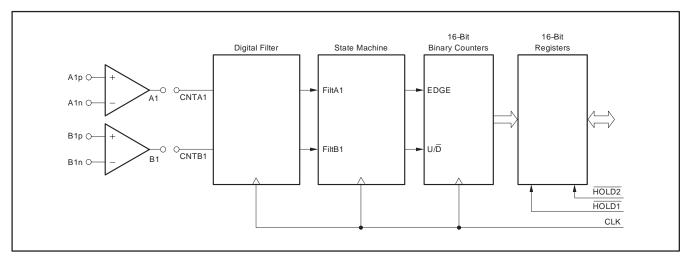


Figure 1-23. Block Diagram of a Counter Module

3.8.1 Operation

Analog position sensors have two signals on the output, sine and cosine. Both signals are differential and positioned at 90 electrical degrees to each other. The sign comparators, with typically 75mV hysteresis, process the position sensor output differential signal. This dramatically reduces the common-mode noise, which is present in motor control applications. The digital output signal from the comparator is connected to the counter input. Extra noise suppression is obtained with Schmitt trigger inputs. The digital signals are carried through a programmable digital filter. The filtered, glitch-free signals are processed by a state machine, which increments or decrements the counters. The counter values are then latched into corresponding registers by the synchronous or asynchronous hold signals HOLD1 and HOLD2.

There is a counter module implemented for each pair of position sensor signals (A1, B1 and A2, B2). These counters can count upwards or downwards, depending on the direction of the position sensor signal (that is, the phase difference of the signals A1 and B1, respectively, or A2 and B2). These counter values are stored in shadow registers when the ADC channels are sampled and held. The four position sensor channels and the counter values are all sampled at the same time on the HOLD1 or HOLD2 signal.

With a 16MHz system clock, the maximum data rate that the counters will operate at is 2MHz.

3.8.2 Digital Noise Filter

A digital noise filter rejects noise on the incoming quadrature signal. The digital noise filter rejects large, short duration, noise spikes; false counts, triggered by noise or spikes, are also significantly suppressed. See Figure 1–24.

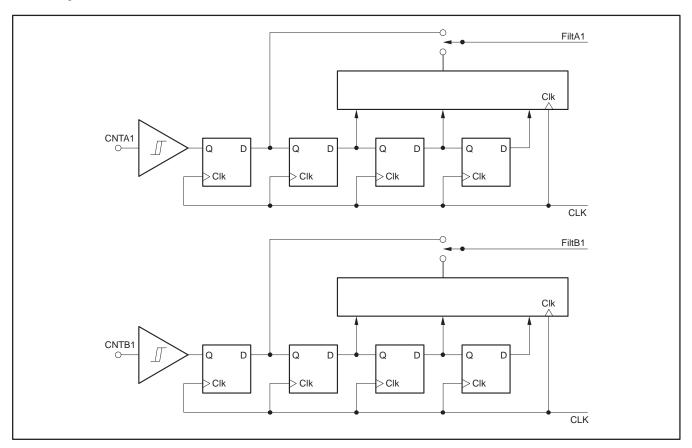


Figure 1-24. Digital Noise Filter Block Diagram

The input signals, Cnt_{XY}, are sampled on the rising clock edge. Before the signals are passed to the state machine, the signals must be stable for a minimum of three consecutive rising clock edges. Pulses shorter than two clock periods are rejected; glitches between rising clock edges are also ignored. See Figure 1–25.



SBAS253C - MAY 2003 - REVISED JANUARY 2005

3.8.2.1 Filtered Timing Characteristics⁽¹⁾

Over recommended operating free-air temperature range at -40° C to $+85^{\circ}$ C, $AV_{DD} = 5V$, $BV_{DD} = 3V - 5V$.

PARAMETER	SYMBOL	MIN	MAX	UNIT
CLK Period	t _{C1}	62.5		ns
Counter input signal, CNTA1 or CNTB1, Period	t _{C2}	8		t _{C1}
Counter input signal, CNTA1 or CNTB1, HIGH or LOW time	t _{W2}	4		t _{C1}
Delay between CNTA1 or CNTB1 signal, any combination	t _{D1}	2		t _{C1}
Filtered noise spike on CNTA1 or CNTB1 input HIGH or LOW Time	t _{W3}		2	t _{C1}

(1) All input signals are specified with $t_R = t_F = 5$ ns (10% to 90% of BV_{DD}) and timed from a voltage level of ($V_{IL} + V_{IH}$)/2.

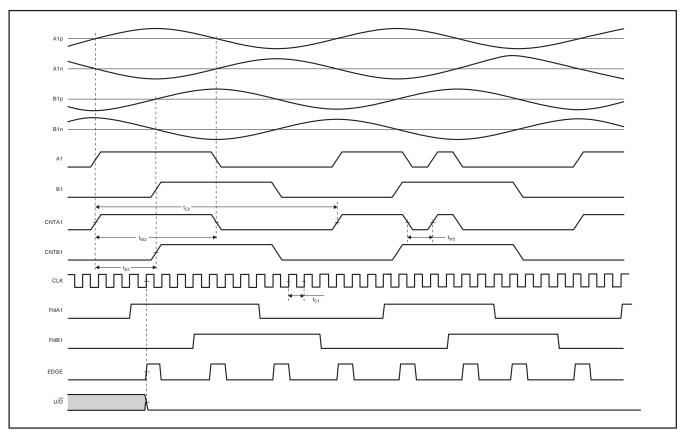


Figure 1-25. Timing Diagram of the Counter Signals with the Digital Noise Filter Enabled

3.8.2.2 Unfiltered Timing Characteristics⁽¹⁾

Over recommended operating free-air temperature range at -40° C to $+85^{\circ}$ C, $AV_{DD} = 5V$, $BV_{DD} = 3V - 5V$.

PARAMETER	SYMBOL	MIN	MAX	UNIT
CLK Period	t _{C1}	62.5		ns
Counter input signal, CNTA1 or CNTB1, Period	t _{C2}	8		t _{C1}
Counter input signal, CNTA1 or CNTB1, HIGH or LOW time	t _{W2}	4		t _{C1}
Delay between CNTA1 or CNTB1 signal, any combination	t _{D1}	2		t _{C1}

(1) All input signals are specified with t_R = t_F = 5ns (10% to 90% of BV_{DD}) and timed from a voltage level of (V_{II} + V_{IH})/2.

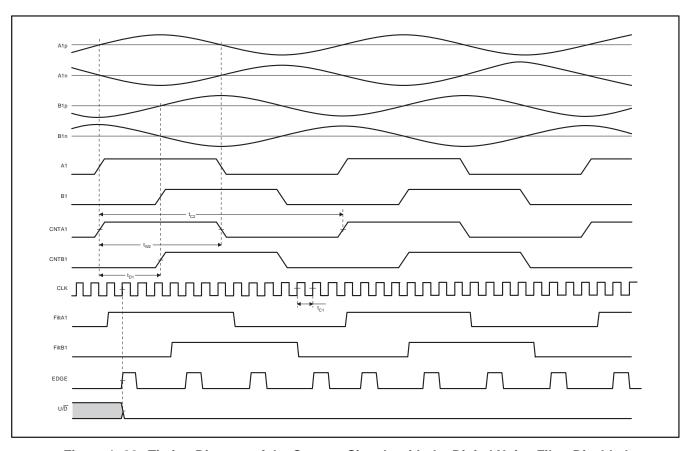


Figure 1-26. Timing Diagram of the Counter Signals with the Digital Noise Filter Disabled



3.8.3 Binary Counters and Registers

The complete up/down counter includes two 16-bit counters and five 16-bit shadow registers. The first counter is a 16-bit up/down counter, which counts upwards or downwards on the EDGE input signal as a function of the U/\overline{D} signal. This is the coarse angle counter, and it is called EDGECNT. For the fine angle computation, the second 16-bit counter, TIMECOUNT, is implemented. This counter increments with the system clock and resets when the EDGE signal occurs. The TIMECOUNT counter cannot be decremented. The system is shown in Figure 1–27 and the timing is shown in Figure 1–28. The U/\overline{D} signal is high, counting upwards, when B1 runs before A1. The U/\overline{D} signal is low, counting downwards, when A1 runs before B1. The EDGE signal is set by every filtered edge of A1 and B1.

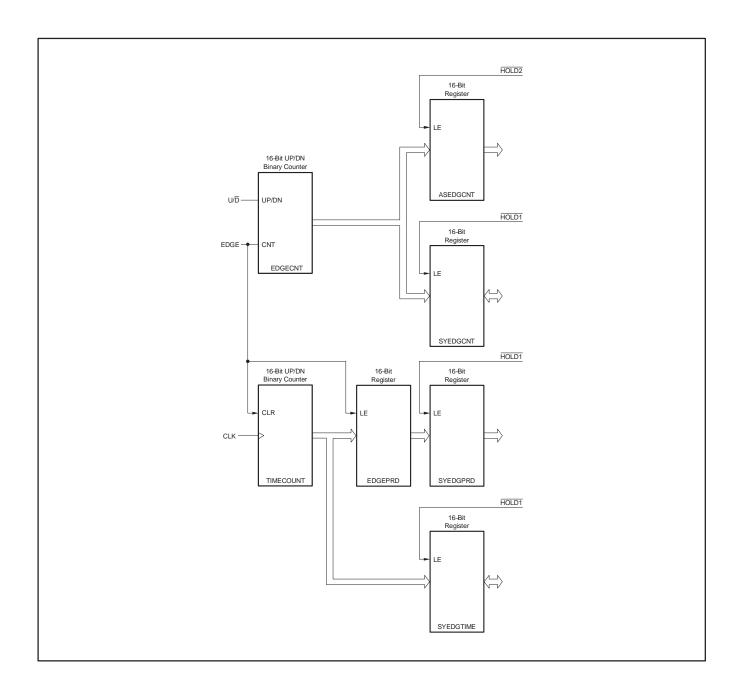


Figure 1-27. Detail Counter Block Diagram



SBAS253C - MAY 2003 - REVISED JANUARY 2005

When EDGECNT cause an over- or under-flow, the corresponding bit in the Interrupt Register is set. The counter continues to increment or decrement in value. When the EDGE signal rises, the TIMECOUNT value is latched into the shadow register EDGEPRD. The value of EDGEPRD is the number of system clocks between two valid edges of the input signals from the comparators. This value is reciprocally proportional to the angular speed of the position sensor. The value in the EDGEPRD register is latched in the SYEDGPRD Register on the synchronous hold signal, $\overline{\text{HOLD1}}$.

The EDGECNT and TIMECOUNT counter values are stored into the shadow registers (SYEDGCNT and SYEDGPRD) with the synchronous hold signal, HOLD1, which samples the analog inputs. The value of the SYEDGTIME Register represents the time between the last EDGE signal and the synchronous hold signal HOLD1. The EDGECNT counter value is stored into a shadow register ASEDGCNT on the asynchronous sample signal HOLD2.

The shadow registers SYEDGCNT, ASEDGCNT, SYEDGPRD and SYEDGTIME can be read through the register map. The counter EDGECNT can be written through the address of the SYEDGCNT Register in the register map. The 14 MSBs of the written data are stored in the EDGECNT register. The two LSBs are determined from the inputs FiltA1 and FiltB1; see the *Edge Count Register* section. This is to prevent inconsistency between the EDGECNT counters and the ADC data of the position sensor input signals.

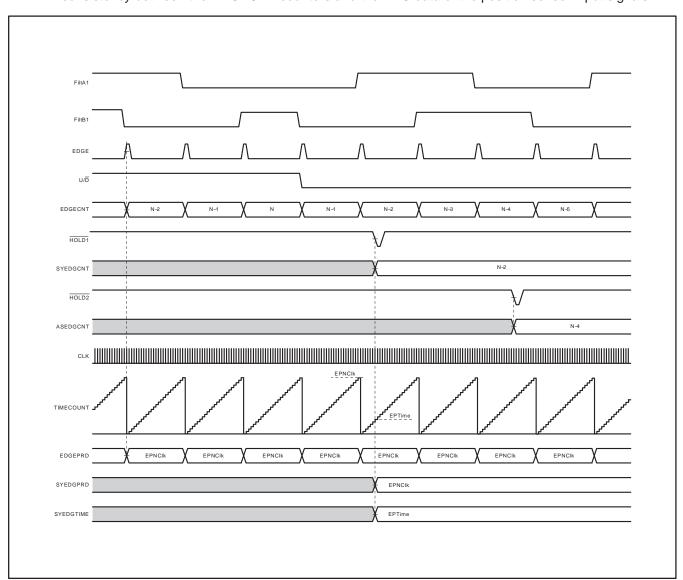


Figure 1–28. Detail Counter Timing Diagram



SBAS253C - MAY 2003 - REVISED JANUARY 2005

3.9 Interrupt

The interrupt can have several sources:

- FIFO full status
- FIFO empty status
- Two TIMECOUNT over- or under-flows
- Two EDGECOUNT over- or under-flows

These six sources are combined into one interrupt signal. The interrupt signal is active high; when the interrupt pin INT is high, one of the six sources is also high.

To reset an interrupt, the Interrupt Register must be read (see *Interrupt Register* section), in order to allow the host to determine which source, or sources, caused the interrupt.

3.10 Reset

The ADS7869 can be forced into a reset state in three different ways:

- Power-on.
- Pulling the RST pin (reset pin 79) low.
- · Writing to the Reset Register.

In addition, the digital counters can be reset via the Reset Register, without resetting the entire ADS7869.

In a reset state, the analog inputs are sampled, the registers (in the register map) are forced into their reset values, and the FIFO and the counters are cleared. One rising clock pulse during a reset condition is necessary to reset the synchronous counters.

It takes one clock cycle for the ADS7869 to begin the normal operation after the last reset condition is cleared. (See Figure 1–29.)

3.10.1 Reset Timing Characteristics⁽¹⁾

Over recommended operating free-air temperature range at -40°C to +85°C, AVDD = 5V, BVDD = 3V - 5V.

PARAMETER	SYMBOL	MIN	MAX	UNIT
Setup time from RST LOW to rising CLK	t _{SU1}	10		ns
Hold time from rising CLK to RST HIGH	t _{H1}	5		ns

(1) All input signals are specified with t_R = t_F = 5ns (10% to 90% of BV_{DD}) and timed from a voltage level of (V_{IL} + V_{IH})/2.

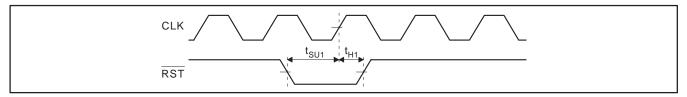


Figure 1–29. Timing Diagram of the Reset Signal RST





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PACKAGING INFORMATION

Orderable Device	Status ⁽¹⁾	Package Type	Package Drawing	Pins	Package Qty	e Eco Plan ⁽²⁾	Lead/Ball Finish	MSL Peak Temp ⁽³⁾
ADS7869IPZT	ACTIVE	TQFP	PZT	100	90	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-4-260C-72 HR
ADS7869IPZTG4	ACTIVE	TQFP	PZT	100	90	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-4-260C-72 HR
ADS7869IPZTR	ACTIVE	TQFP	PZT	100	1000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-4-260C-72 HR
ADS7869IPZTRG4	ACTIVE	TQFP	PZT	100	1000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-4-260C-72 HR

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

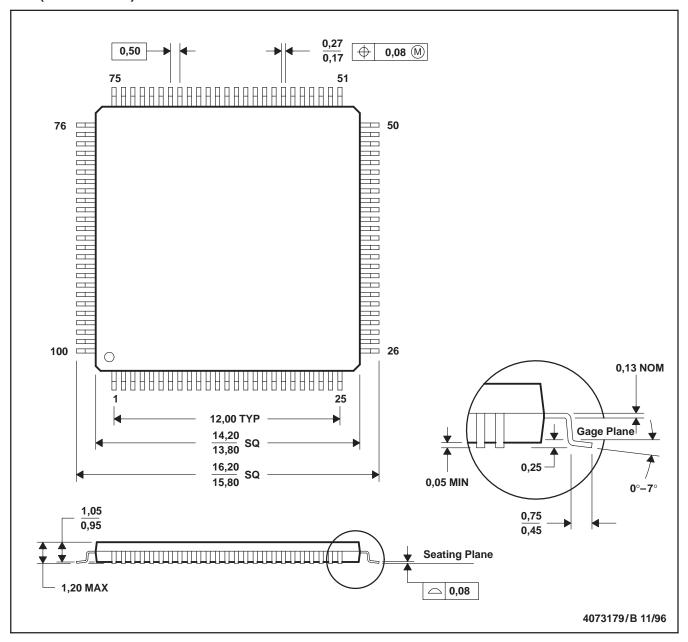
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PZT (S-PQFP-G100)

PLASTIC QUAD FLATPACK

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NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Falls within JEDEC MS-026